

2N4108 • 2N4109 • 2N4110

PNPN SILICON CONTROLLED RECTIFIERS

DIFFUSED SILICON PLANAR DEVICES

- OPERATION TO 125°C GUARANTEED WITH NO FORWARD OR REVERSE VOLTAGE DERATING.
- LOW FORWARD "ON" VOLTAGE GUARANTEED AT 3 POINTS.
- LOW FORWARD AND REVERSE LEAKAGES GUARANTEED.
- PLANAR RELIABILITY BUILT IN.

ABSOLUTE MAXIMUM RATINGS (Note 1)

Maximum Temperatures

Storage Temperature

– 65°C to + 125°C

Operating Junction Temperature

– 65°C to + 125°C

Lead Temperature (Soldering, 10 sec. time limit)

+ 260°C Maximum

Maximum Power Dissipation

Average Gate Power Dissipation at 25°C Ambient Temperature (Note 2)

0.1 Watt

Maximum Currents

DC Forward Current at 25°C Case Temperature (Note 2)

1.0 Amp.

DC Forward Current at 25°C Ambient Temperature

235 mA

Surge Current at 25°C Ambient Temperature (Note 2)

4.0 Amps.

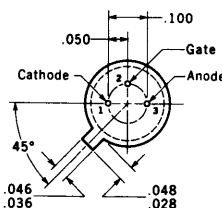
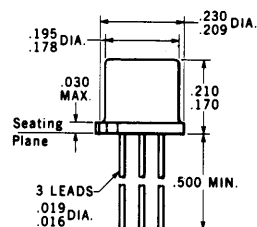
(½ cycle sine wave = 8.3 msec)

Average Forward Current at 25°C Ambient Temperature 180° Conduction

180 mA

PHYSICAL DIMENSIONS

in accordance with
JEDEC (TO-18) outline



NOTES: All dimensions in inches
Leads are gold-plated kovar
Anode internally connected to case
Package weight is 0.44 gram

ELECTRICAL CHARACTERISTICS (25°C Free Air Temperature unless otherwise specified)

SYMBOL	CHARACTERISTICS	MIN	TYP	MAX	UNITS	TEST CONDITIONS
V_{FX}	Forward Blocking Voltage ($T_A = -65^\circ\text{C}$ to $+125^\circ\text{C}$)	2N4108	50		Volts	$I_{FX} = 0.05 \mu\text{A}$, $R_{GK} = 1.0 \text{ k}\Omega$
		2N4109	100		Volts	
		2N4110	200		Volts	
V_{RO}	Reverse Blocking Voltage ($T_A = -65^\circ\text{C}$ to $+125^\circ\text{C}$)	2N4108	50		Volts	$I_{RO} = 0.05 \mu\text{A}$, $R_{GK} = \infty$
		2N4109	100		Volts	
		2N4110	200		Volts	
I_{FX}	Forward Blocking Current (at rated V_{FX})		8	50	nA	$R_{GK} = 1.0 \text{ k}\Omega$
$I_{FX} (125^\circ\text{C})$	Forward Blocking Current (at rated V_{FX})		5	20	μA	$R_{GK} = 1.0 \text{ k}\Omega$
I_{RO}	Reverse Blocking Current (at rated V_{RO})		8	50	nA	$R_{GK} = \infty$
$I_{RO} (125^\circ\text{C})$	Reverse Blocking Current (at rated V_{RO})		5	20	μA	$R_{GK} = \infty$
I_{GT}	Gate Trigger Current		0.060	0.2	mA	$V_{AK} = 10\text{V}$, $R_L = 100\Omega$
$I_{GT} (-55^\circ\text{C})$	Gate Trigger Current		0.110	2.0	mA	$V_{AK} = 10\text{V}$, $R_L = 100\Omega$
V_{GT}	Gate Trigger Voltage		0.58	0.8	Volts	$V_{AK} = 10\text{V}$, $R_L = 100\Omega$
$V_{GT} (-55^\circ\text{C})$	Gate Trigger Voltage		0.75	1.1	Volts	$V_{AK} = 10\text{V}$, $R_L = 100\Omega$
$V_{GT} (125^\circ\text{C})$	Gate Trigger Voltage (at rated V_{FX})	0.2	0.4		Volts	$R_L = 10 \text{ k}\Omega$

Additional Electrical Characteristics on page 2

NOTES:

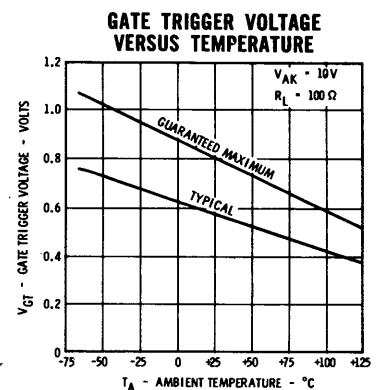
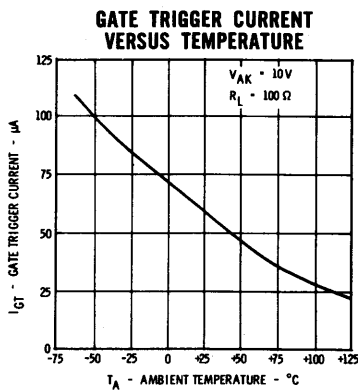
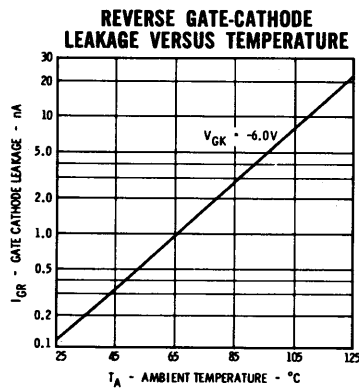
(1) These ratings are limiting values above which the serviceability of any semiconductor device may be impaired.

(2) These ratings give a maximum junction temperature of 125°C and junction to case thermal resistance of 44.5°C/Watt (derating factor of 22.5 mW/°C); junction to ambient thermal resistance of 350°C/W (derating factor of 2.84 mW/°C).

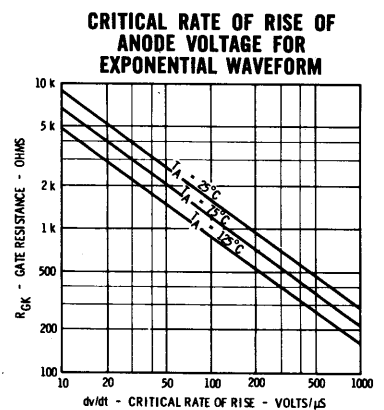
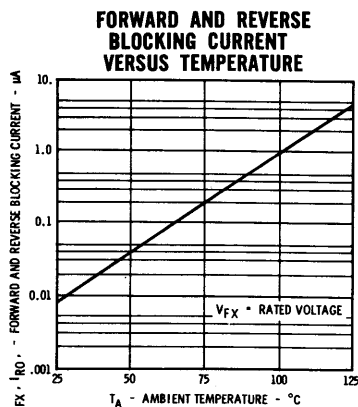
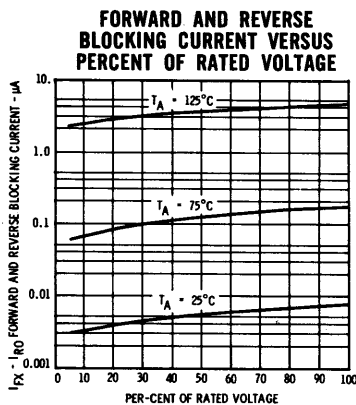
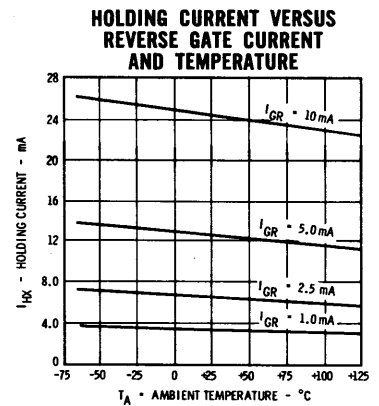
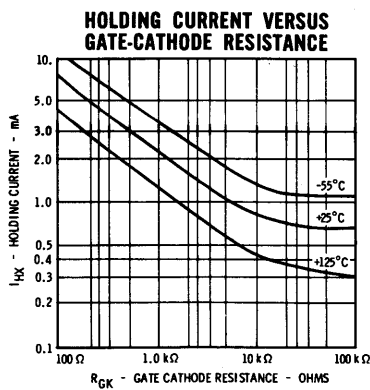
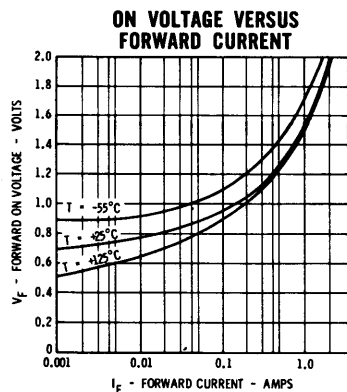
ELECTRICAL CHARACTERISTICS (25°C Free Air Temperature unless otherwise specified)

SYMBOL	CHARACTERISTICS	MIN	TYP	MAX	UNITS	TEST CONDITIONS
V_F	On Voltage		0.95	1.15	Volts	$I_F = 175 \text{ mA}$
V_F	On Voltage		1.05	1.2	Volts	$I_F = 250 \text{ mA}$
V_F	On Voltage		1.2	1.6	Volts	$I_F = 500 \text{ mA}$
I_{HO}	Holding Current		0.7	2.0	mA	$R_G = \infty, R_L = 1.0 \text{ K}\Omega$
I_{GR}	Gate Leakage Current		0.13	25	nA	$I_F = 0, V_{GK} = -6.0 \text{ V}$
$I_{GR} (125^\circ\text{C})$	Gate Leakage Current		0.024	10	μA	$I_F = 0, V_{GK} = -6.0 \text{ V}$
t_{on}	Turn On Time		0.56	1.5	μs	$I_F \approx 200 \text{ mA}, I_{GF} = 10 \text{ mA}$
t_{off}	Turn Off Time (see t_{off} circuit)		6.5	15	μs	$I_F = I_R \approx 200 \text{ mA}$
dv/dt	Critical Rate of Rise (at rated V_{FX})	75	200		Volts/ μs	$R_{GK} = 1 \text{ K}\Omega, R_L = 100 \Omega$

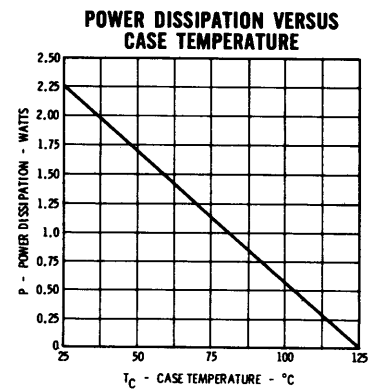
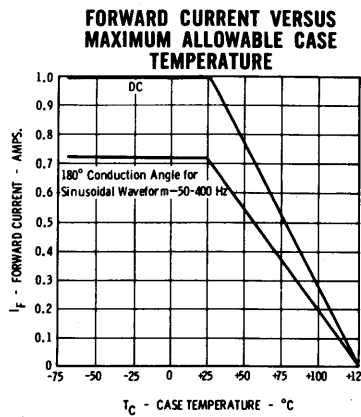
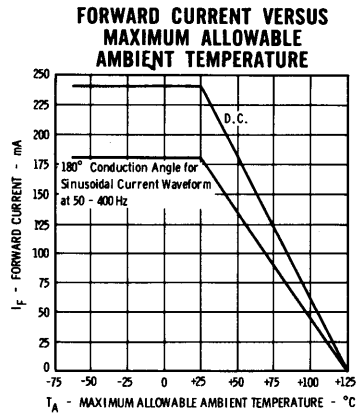
GATE CHARACTERISTICS



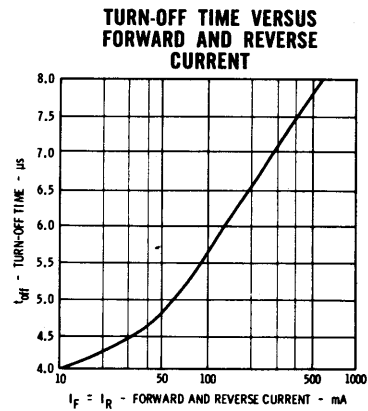
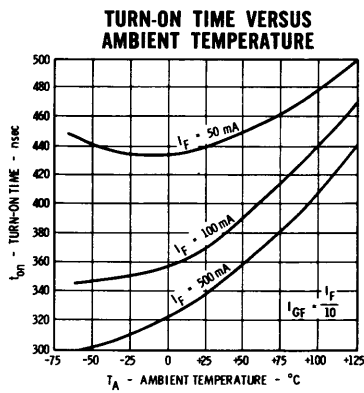
TYPICAL ELECTRICAL CHARACTERISTICS



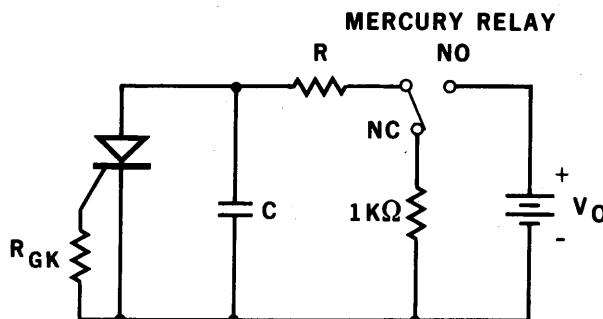
MAXIMUM RATINGS



SWITCHING CHARACTERISTICS



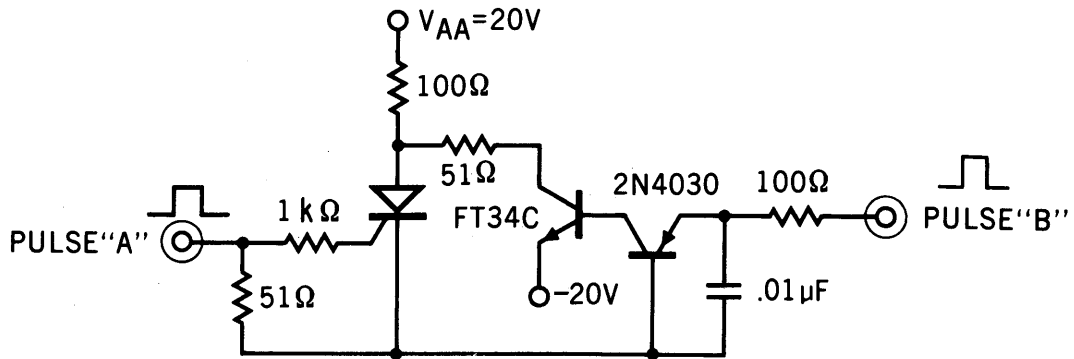
$\frac{dv}{dt}$ CIRCUIT



$$\frac{dv}{dt} = 0.632 \frac{V_O}{RC}$$

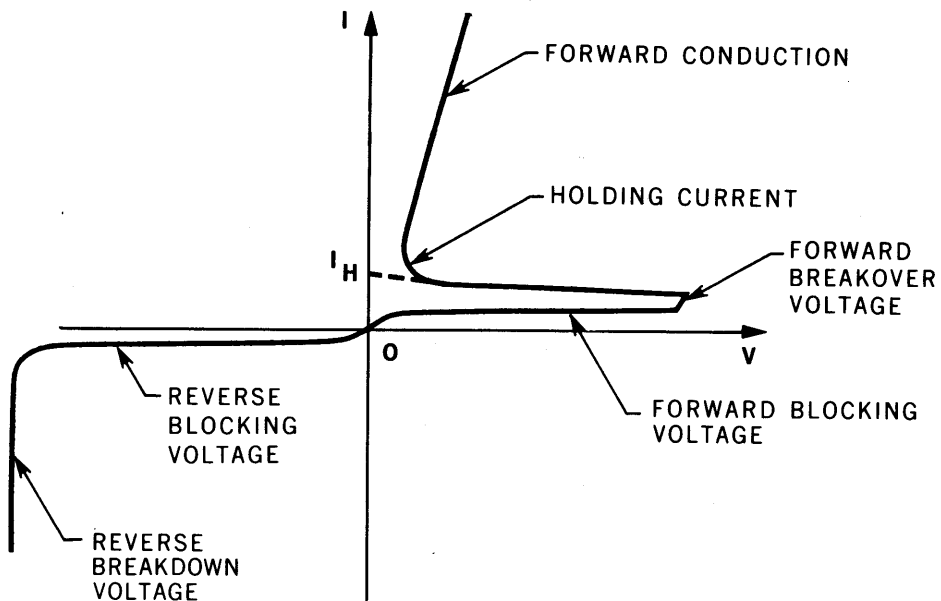
V_O = RATED VOLTAGE

t_{off} CIRCUIT



PULSE B DELAYED FROM PULSE A BY APPROXIMATELY 100 μ s

ANODE CHARACTERISTIC



2N4115 • 2N4116

NPN POWER TRANSISTORS

DIFFUSED SILICON PLANAR EPITAXIAL TRANSISTORS

REPLACES FT7207A • FT7207B

- HIGH POWER — 37 WATTS @ $T_c = 100^\circ\text{C}$
- HIGH VOLTAGE (V_{CEO}) — 80 VOLTS MIN.
- HIGH CURRENT ($V_{CE \text{ sat}}$) — 1.5 VOLTS MAX. @ 5.0 AMPS.
- BETA GUARANTEED @ 3 POINTS — 50 mA, 2 AMPS. and 5 AMPS.
- HIGH (f_T) — 70 and 80 MHz MIN. @ 0.5 AMP.
- ISOLATED COLLECTOR PACKAGE
- SAFE AREA EXTENDED BY USE OF NICHROME THIN FILM EMITTER RESISTOR

ABSOLUTE MAXIMUM RATINGS [Note 1]

Maximum Temperatures

Storage Temperature
Operating Junction Temperature
Lead Temperature (Soldering, 60 sec time limit)

Maximum Power Dissipation

Total Dissipation at 100°C Case Temperature
(See safe operating area and derating curves)
Thermal Resistance

Maximum Voltages

V_{CBO} Collector to Base Voltage
 V_{CEO} Collector to Emitter Voltage [Note 2]
 V_{EBO} Emitter to Base Voltage

-65°C to $+200^\circ\text{C}$
 -65°C to $+200^\circ\text{C}$
 300°C Maximum

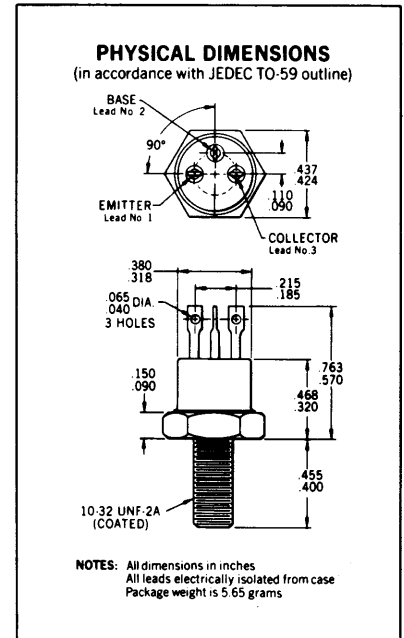
37 Watts

2.7°C/W

120 Volts

80 Volts

8.0 Volts



ELECTRICAL CHARACTERISTICS (25°C Case Temperature unless otherwise noted)

SYMBOL	CHARACTERISTIC	2N4115			2N4116			UNITS	TEST CONDITIONS
		MIN.	TYP.	MAX.	MIN.	TYP.	MAX.		
* h_{FE}	DC Pulse Current Gain [Note 3]	40	63	120	100	139	300		$I_C = 2.0 \text{ A}$ $V_{CE} = 5.0 \text{ V}$
h_{FE}	DC Pulse Current Gain [Note 3]	20	45		40	100			$I_C = 5.0 \text{ A}$ $V_{CE} = 5.0 \text{ V}$
$V_{CE \text{ (sat)}}$	Pulsed Collector Saturation Voltage [Note 3]		0.5	1.5		0.5	1.5	Volts	$I_C = 5.0 \text{ A}$ $I_B = 0.5 \text{ A}$
$V_{BE \text{ (sat)}}$	Pulsed Base Saturation Voltage [Note 3]		1.3	2.2		1.3	2.2	Volts	$I_C = 5.0 \text{ A}$ $I_B = 0.5 \text{ A}$
* $V_{CE \text{ (sat)}}$	Pulsed Collector Saturation Voltage [Note 3]		0.22	0.6		0.22	0.6	Volts	$I_C = 2.0 \text{ A}$ $I_B = 0.2 \text{ A}$
* $V_{BE \text{ (sat)}}$	Pulsed Base Saturation Voltage [Note 3]		0.95	1.3		0.95	1.3	Volts	$I_C = 2.0 \text{ A}$ $I_B = 0.2 \text{ A}$
$V_{CEO \text{ (sust)}}$	Collector to Emitter Sustaining Voltage [Notes 2 and 3]	80			80			Volts	$I_C = 50 \text{ mA}$ $I_B = 0$ (pulsed)
BV_{CES}	Collector to Emitter Breakdown Voltage	120			120			Volts	$I_C = 2.0 \text{ mA}$ $V_{BE} = 0$
BV_{EBO}	Emitter to Base Breakdown Voltage	8.0			8.0			Volts	$I_C = 0$ $I_E = 1.0 \text{ mA}$

Notes on page 2

Additional Electrical Characteristics on page 2

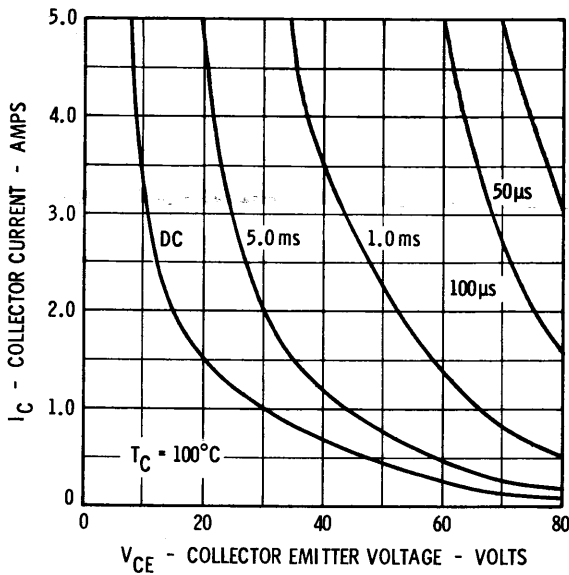
FAIRCHILD
SEMICONDUCTOR
A DIVISION OF FAIRCHILD CAMERA AND INSTRUMENT CORPORATION

FAIRCHILD TRANSISTORS 2N4115 • 2N4116

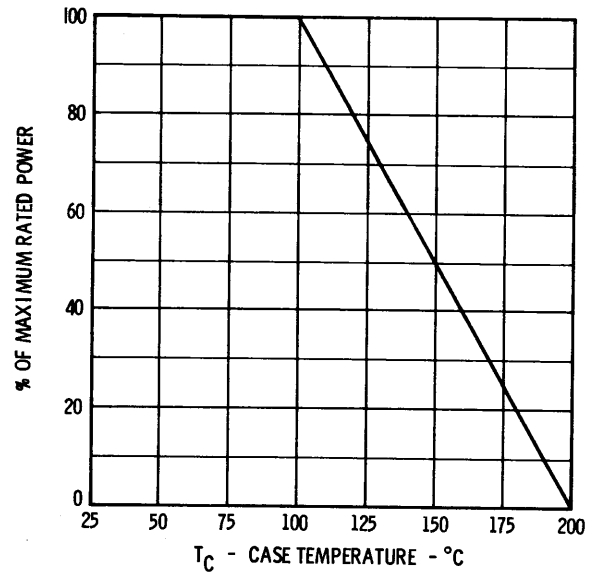
ELECTRICAL CHARACTERISTICS (25°C Case Temperature unless otherwise noted)

SYMBOL	CHARACTERISTIC	2N4115			2N4116			UNITS	TEST CONDITIONS
		MIN.	TYP.	MAX.	MIN.	TYP.	MAX.		
* I_{CES}	Collector Reverse Current			10			10	μA	$V_{CE} = 60 V$ $V_{BE} = 0$
I_{CEO}	Collector Cutoff Current			50			50	μA	$I_B = 0$ $V_{CE} = 40 V$
$I_{CEX} (150^\circ C)$	Collector Cutoff Current			100			100	μA	$V_{CE} = 60 V$ $V_{EB} = 2.0 V$
I_{EBO}	Emitter Cutoff Current			25			25	μA	$I_C = 0$ $V_{EB} = 6.0 V$
h_{FE}	DC Pulse Current Gain [Note 3]	20	40		40	72			$I_C = 50 mA$ $V_{CE} = 5.0 V$
$h_{FE} (-55^\circ C)$	DC Pulse Current Gain [Note 3]	15	34		35	82			$I_C = 2.0 A$ $V_{CE} = 5.0 V$
h_{fe}	High Frequency Current Gain ($f = 20 MHz$)	3.5	6.75		4.0	9.75			$I_C = 0.5 A$ $V_{CE} = 5.0 V$
C_{obo}	Output Capacitance		80	120		80	120	pF	$I_E = 0$ $V_{CE} = 10 V$
C_{ibo}	Input Capacitance		450	700		450	700	pF	$I_C = 0$ $V_{EB} = 2.0 V$
h_{fe}	Small Signal Current Gain ($f = 1 kHz$)	20			40				$I_C = 50 mA$ $V_{CE} = 5.0 V$
$V_{BE} (ON)$	Pulsed Base Emitter ON Voltage [Note 3]		1.3			1.3		Volts	$I_C = 2.0 A$ $V_{CE} = 5.0 V$

FORWARD BIASED SAFE OPERATING AREA



DERATING CURVE

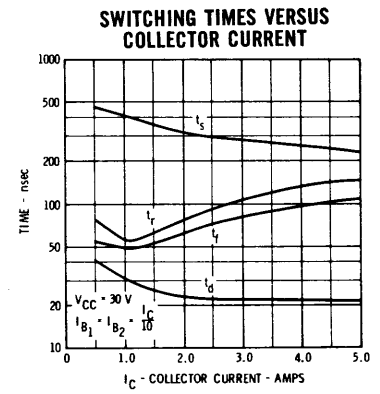
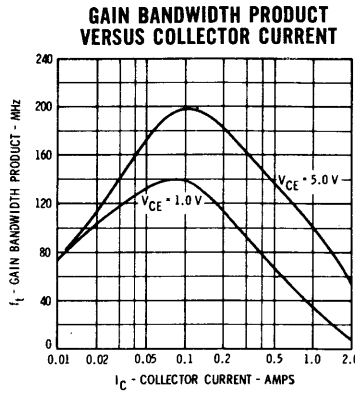
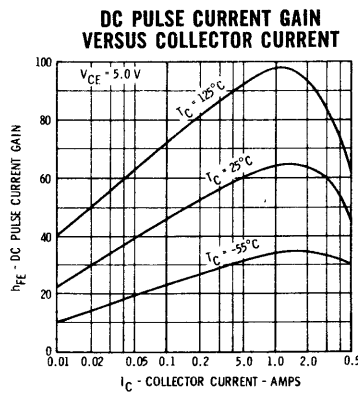
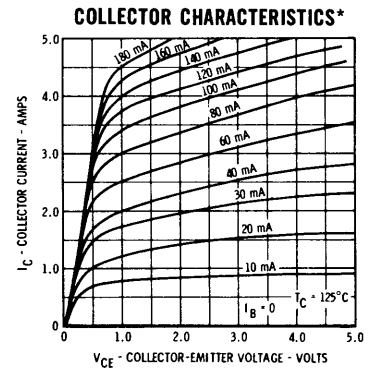
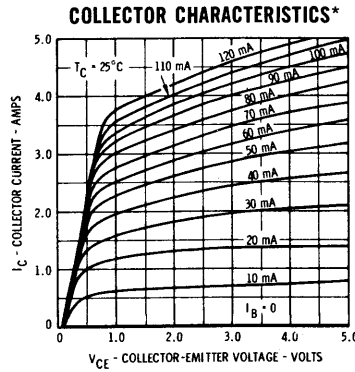
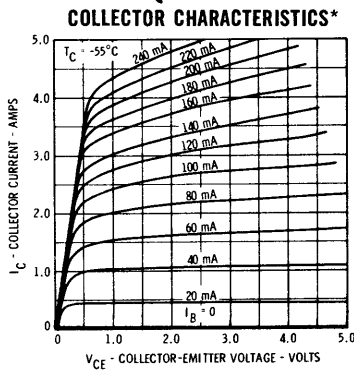


NOTES:

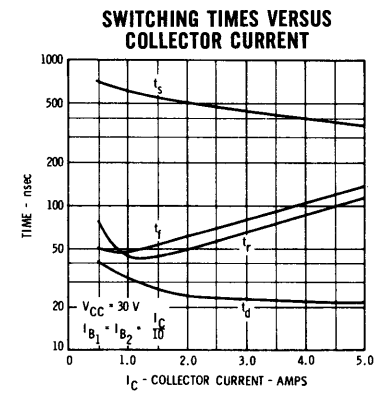
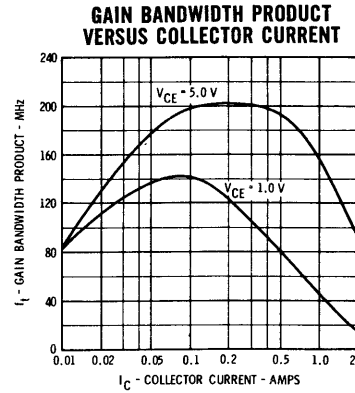
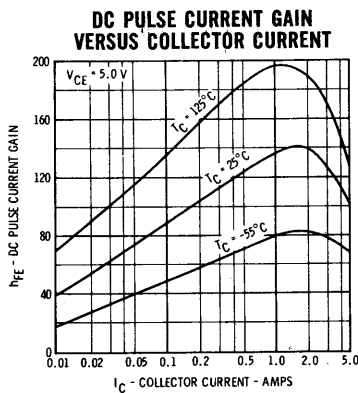
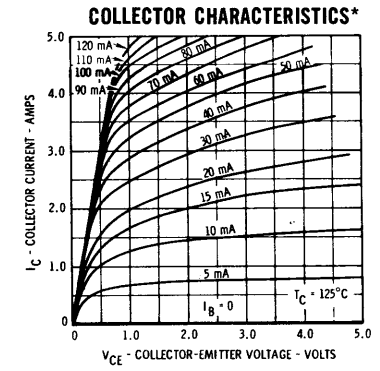
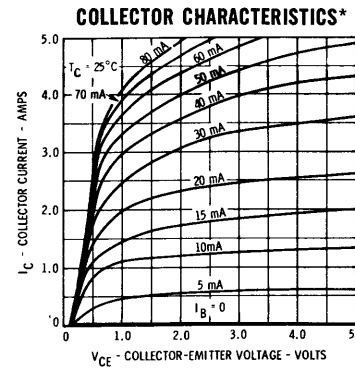
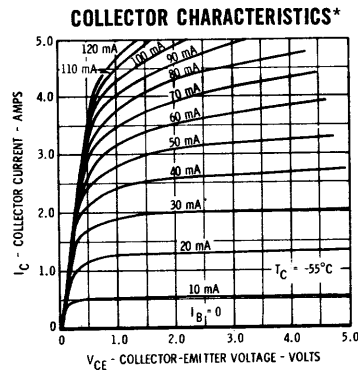
- (1) These ratings are limiting values above which the serviceability of any semiconductor device may be impaired.
- (2) This rating refers to a high-current point where collector to emitter voltage is lowest. For more information send for Fairchild Publication APP-4/2.
- (3) Pulse conditions: length = 300 μs ; duty cycle = 1%.

TYPICAL ELECTRICAL CHARACTERISTICS

2N4115



2N4116



* Single family characteristic on Transistor Curve Tracer.

2N4134 • 2N4135

NPN LOW NOISE RF AMPLIFIERS

DIFFUSED SILICON PLANAR* TRANSISTORS

- **LOW NOISE FIGURE** -- 2.5 db MAX @ 60 MHz
5.0 db MAX @ 450 MHz
- **HIGH STABLE GAIN IN UNNEUTRALIZED AMPLIFIERS** -- 20 db MIN @ 60 MHz
8 db MIN @ 450 MHz

- **LOW FEEDBACK CAPACITANCE** -- 0.5 pF MAX
- **GUARANTEED FORWARD AGC**

ABSOLUTE MAXIMUM RATINGS [Note 1]

Maximum Temperatures

Storage Temperature
Operating Junction Temperature

Maximum Power Dissipation

Total Dissipation at 25°C Case Temperature [Note 2]
at 25°C Ambient Temperature [Note 2]

Maximum Voltages

V_{CBO} Collector to Base Voltage
 V_{CEO} Collector to Emitter Voltage [Note 3]
 V_{EBO} Emitter to Base Voltage

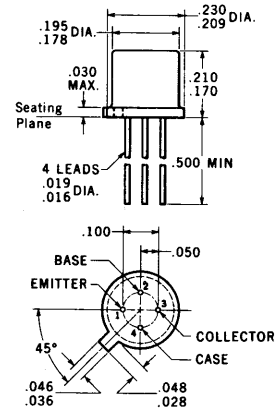
-55°C to +200°C
+200°C

0.3 Watt
0.2 Watt

30 Volts
30 Volts
3.0 Volts

PHYSICAL DIMENSIONS

in accordance with
JEDEC (TO-72)



ELECTRICAL CHARACTERISTICS (25°C Free Air Temperature Unless Otherwise Specified)

SYMBOL	CHARACTERISTIC	MIN.	TYP.	MAX.	UNITS	TEST CONDITIONS
NF	Noise Figure (f = 450 MHz) [Note 5]			5.0	dB	$I_E = 1.0 \text{ mA}$ $V_{CB} = 15 \text{ V}$ $R_s \approx 130 \Omega$
PG	Power Gain (f = 450 MHz) (Adjusted for min. Noise Figure; Note 5)	8.0	10			$I_E = 1.0 \text{ mA}$ $V_{CB} = 15 \text{ V}$
NF	Noise Figure (f = 60 MHz) [Note 6]		2.0	2.5	dB	$I_E = 1.0 \text{ mA}$ $V_{CB} = 15 \text{ V}$ $R_s \approx 300 \Omega$
PG	Power Gain, Neutralized (f = 60 MHz) (Adjusted for min. Noise Figure; Note 6)	17	21	24	dB	$I_E = 1.0 \text{ mA}$ $V_{CB} = 15 \text{ V}$
PG	Power Gain, Unneutralized (f = 60 MHz) [Note 7]	20	23	25	dB	$I_E = 5.0 \text{ mA}$ $V_{AGC} = 13 \text{ V}$
V_{AGC}	AGC Voltage for 30 db Gain Reduction (f = 60 MHz) [Note 7]	19	22	24.5	Volts	$V_{CC} = 28 \text{ V}$
$r_o' C_c$	Collector-Base Time Constant (f = 80 MHz)		2.5	5.0	ps	$I_C = 4.0 \text{ mA}$ $V_{CE} = 10 \text{ V}$
f_{max}	Maximum Frequency of Oscillation		3.25		GHz	$I_E = 4.0 \text{ mA}$ $V_{CB} = 15 \text{ V}$
C_{cb}	Reverse Transfer Capacity Common Emitter	0.25	0.37	0.50	pF	$I_E = 0$ $V_{CE} = 10 \text{ V}$ f = 1.0 MHz (Emitter & Can Guarded)
h_{fo}	High Frequency Current Gain (f = 100 MHz)	4.25		8.0		$I_C = 4.0 \text{ mA}$ $V_{CE} = 10 \text{ V}$
h_{fo}	High Frequency Current Gain (f = 100 MHz)	3.5		8.0		$I_C = 4.0 \text{ mA}$ $V_{CE} = 10 \text{ V}$
h_{FE}	DC Pulse Current Gain [Note 4]	25		200		$I_C = 4.0 \text{ mA}$ $V_{CE} = 10 \text{ V}$
$h_{FE} (-55^\circ\text{C})$	DC Pulse Current Gain [Note 4]	10				$I_C = 4.0 \text{ mA}$ $V_{CE} = 10 \text{ V}$
$V_{CEO} (\text{sust})$	Collector to Emitter Sustaining Voltage [Notes 3 and 4]	30			Volts	$I_C = 1.0 \text{ mA}$ $I_B = 0$
BV_{CBO}	Collector to Base Breakdown Voltage	30			Volts	$I_C = 1.0 \text{ mA}$ $I_E = 0$
BV_{EBO}	Emitter to Base Breakdown Voltage	3.0			Volts	$I_C = 0$ $I_E = 100 \mu\text{A}$
$V_{BE} (\text{sat})$	Base Saturation Voltage		0.92		Volt	$I_C = 10 \text{ mA}$ $I_B = 5.0 \text{ mA}$
$V_{CE} (\text{sat})$	Collector Saturation Voltage		3.0		Volts	$I_C = 10 \text{ mA}$ $I_B = 5.0 \text{ mA}$
$I_{CBO} (150^\circ\text{C})$	Collector Cutoff Current		50		μA	$I_E = 0$ $V_{CB} = 10 \text{ V}$
$I_{CBO} (25^\circ\text{C})$	Collector Cutoff Current		50		nA	$I_E = 0$ $V_{CB} = 10 \text{ V}$

* Planar is a patented Fairchild process.

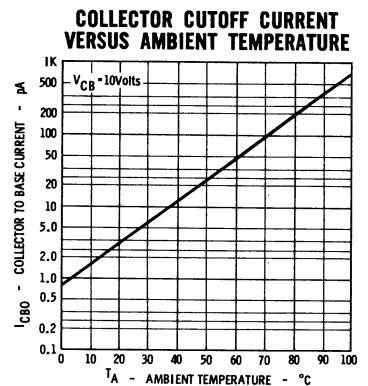
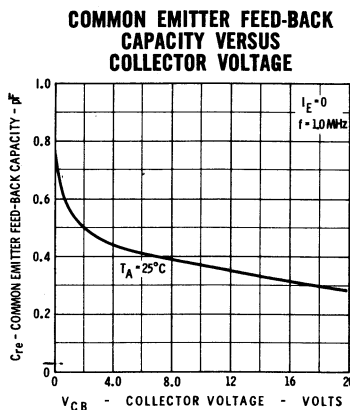
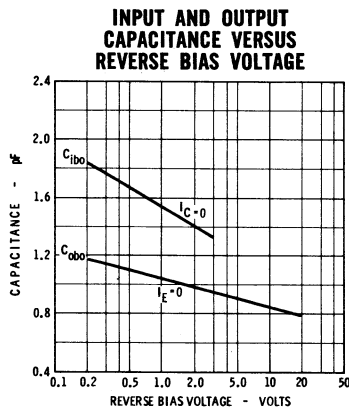
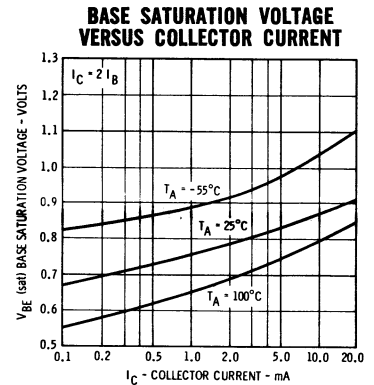
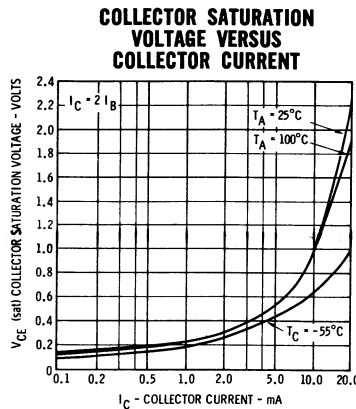
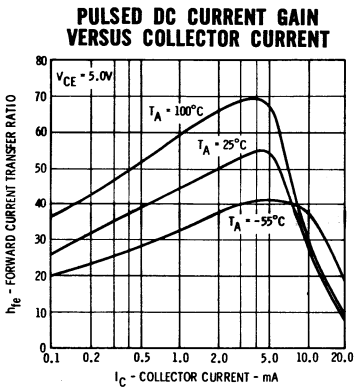
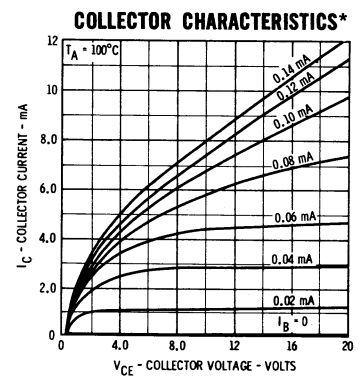
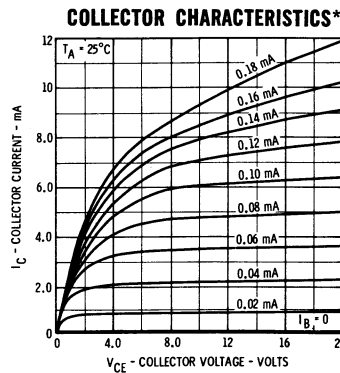
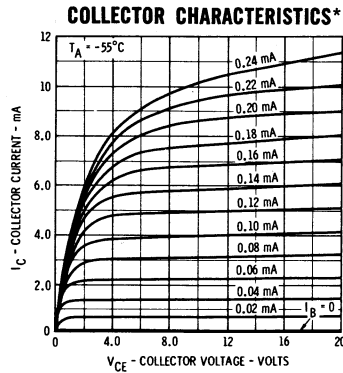
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FAIRCHILD TRANSISTORS 2N4134 • 2N4135

NOTES:

- (1) These ratings are limiting values above which the serviceability of any individual semiconductor device may be impaired.
- (2) These ratings give a maximum junction temperature of 200°C and junction to case thermal resistance of 583°C/Watt (derating factor 1.72 mW/°C); junction to ambient thermal resistance of 875°C/Watt (derating factor of 1.14 mW/°C).
- (3) Rating refers to a high-current point where collector to emitter voltage is lowest.
- (4) Pulse Conditions: length = 300 μ s; duty cycle = 1%.
- (5) Test conditions are as shown in Figure 1. Noise Figure referenced to AIL type 70 Hot-Cold noise standard. Noise Figure includes second stage contribution of 5.0 db.
- (6) Test conditions are as shown in Figure 2. Amplifier Gain is measured with amplifier input tuned for minimum noise figure. Neutralization is used to minimize input bandpass skewing. With neutralization network removed, amplifier gain will be 2 to 3 db lower, but noise figure will not change measurably.
- (7) Test conditions are as shown in Figure 3.
- (8) Socket Capacitance is typically 0.5 pF and will degrade amplifier gain and stability. Best performance is obtained by omitting sockets and soldering or clipping transistor to the ground plane. If a socket is required, a shield should be used between the base and collector socket pins.

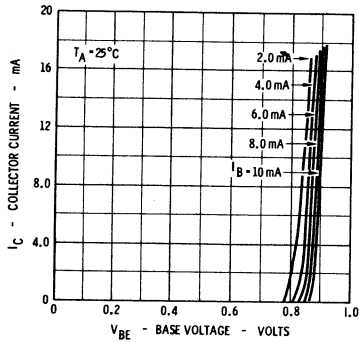
TYPICAL ELECTRICAL CHARACTERISTICS



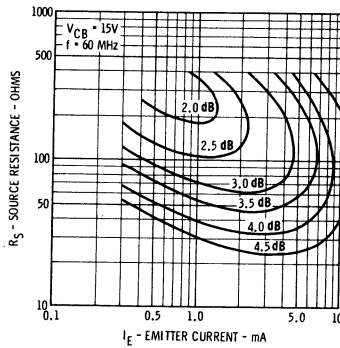
* Single family characteristic on Transistor Curve Tracer.

FAIRCHILD TRANSISTORS 2N4134 • 2N4135

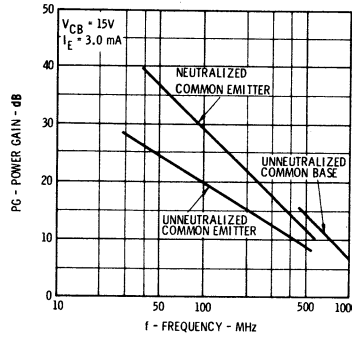
BASE CHARACTERISTICS*



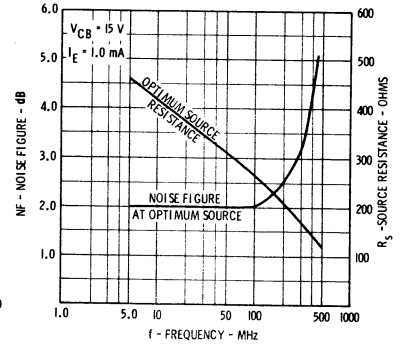
NOISE FIGURE VERSUS SOURCE RESISTANCE AND COLLECTOR CURRENT



POWER GAIN VERSUS FREQUENCY

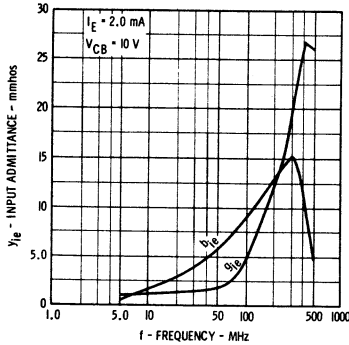


NOISE FIGURE AND SOURCE RESISTANCE VERSUS FREQUENCY

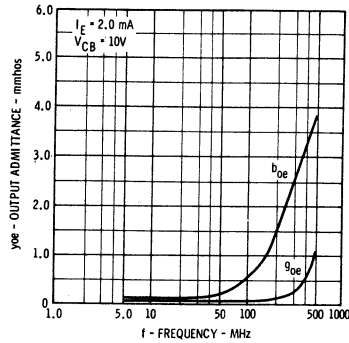


TYPICAL "Y" PARAMETERS

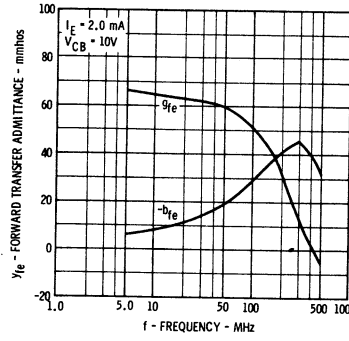
INPUT ADMITTANCE VERSUS FREQUENCY — OUTPUT SHORT CIRCUIT



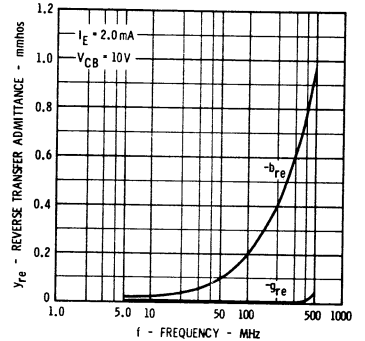
OUTPUT ADMITTANCE VERSUS FREQUENCY — INPUT SHORT CIRCUIT



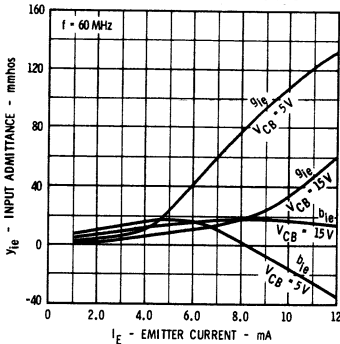
FORWARD TRANSFER ADMITTANCE VERSUS FREQUENCY — INPUT SHORT CIRCUIT



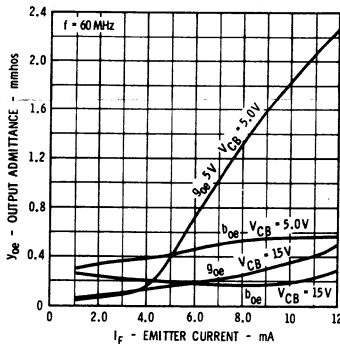
REVERSE TRANSFER ADMITTANCE VERSUS FREQUENCY — OUTPUT SHORT CIRCUIT



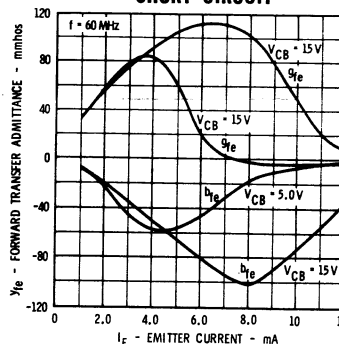
INPUT ADMITTANCE VERSUS EMITTER CURRENT — OUTPUT SHORT CIRCUIT



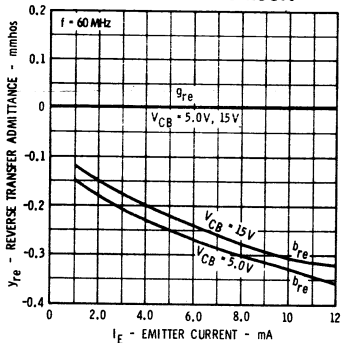
OUTPUT ADMITTANCE VERSUS EMITTER CURRENT — INPUT SHORT CIRCUIT



FORWARD TRANSFER ADMITTANCE VERSUS EMITTER CURRENT — OUTPUT SHORT CIRCUIT

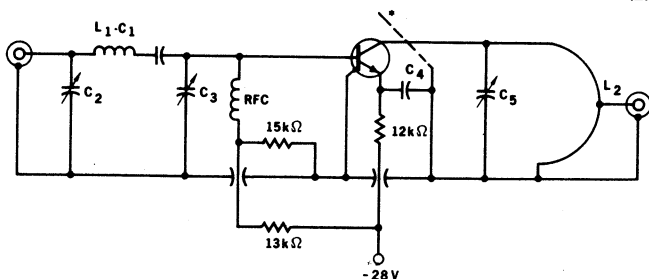


REVERSE TRANSFER ADMITTANCE VERSUS EMITTER CURRENT — INPUT SHORT CIRCUIT



* Single family characteristic on Transistor Curve Tracer.

FIG. 1 450 MHz NOISE FIGURE AND POWER GAIN CIRCUIT (2N4135 only)



$L_1 - C_1$ 300 pF, PORCELAIN CAPACITOR: CAPACITOR LEADS FORM L_1 : LEAD DIAMETER 0.025, LENGTH 1-3/8" FROM INPUT CONNECTOR TO BASE PIN OF TRANSISTOR (VITRAMON VY 12C301 OR EQUIVALENT)

L_2 1 TURN, #22 TINNED WIRE 1/2" DIAMETER, 5/16" LONG, CENTER TAP

C_2, C_3, C_5 0.8 - 10 pF, AIR VARIABLE (JOHANSEN 2950 OR EQUIVALENT)

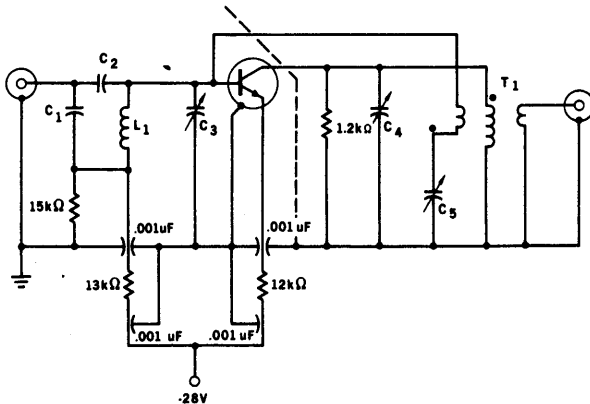
C_4 500 pF, UNCASSED CERAMIC (CENTRALAB DA121 OR EQUIVALENT)

RFC 6" #30 ENAMEL WIRE, CLOSE WOUND, 1/16" DIAMETER FEEDTHROUGH CAPACITORS ARE 1000pF CERAMIC (ALLEN-BRADLEY FASC OR EQUIVALENT)

*See Note 8

FAIRCHILD TRANSISTORS 2N4134 • 2N4135

FIG. 2 60 MHz NOISE FIGURE AND POWER GAIN CIRCUIT



C_1 - 62 pF DIPPED MICA CAPACITOR

C_2 - 51 pF DIPPED MICA CAPACITOR

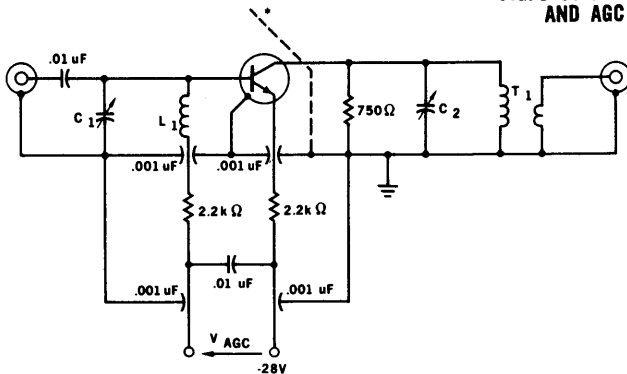
C_3, C_4, C_5 - 0.8 - 10 pF, AIR VARIABLE, (JOHANSEN 2950 OR EQUIVALENT)

APPROXIMATE CAPACITANCE,

L_1 - 5 TURNS NUMBER 18 ENAMEL WIRE, AIR WOUND, 5/16" INSIDE DIAMETER, 3/8" LONG, INDUCTANCE 0.14 μ H.

T_1 - PRIMARY: 14 TURNS NUMBER 24 ENAMEL WIRE SPACED EVENLY AROUND 0.156" I.D. TOROID (ARNOLD A4-310-125 SF OR EQUIVALENT) INDUCTANCE 0.82 μ H, SECONDARY: 3 TURNS, NEUTRALIZATION WINDING: 3 T CLOSE WOUND BYPASS AND FEEDTHROUGH CAPACITORS ARE 1000 pF CERAMIC (ALLEN-BRADLEY FASC OR EQUIVALENT)

FIG. 3 60 MHz POWER GAIN AND AGC CIRCUIT



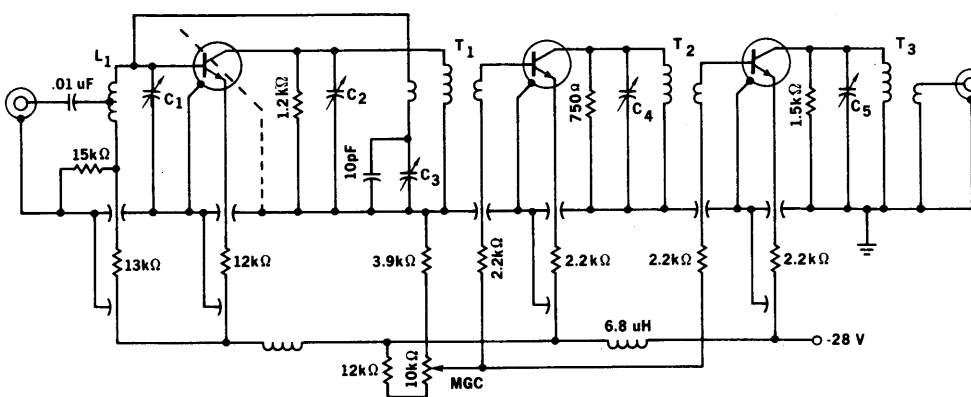
L_1 - 7 TURNS, NUMBER 22 ENAMEL WIRE WOUND ON 0.156" I.D. TOROID FORM, ARNOLD ENGINEERING COMPANY, TYPE A4-310-125-SF, OR EQUIVALENT, INDUCTANCE 0.21 μ H.

T_1 - PRIMARY: 14 TURNS, NUMBER 24 ENAMEL WIRE WOUND ON TOROID, INDUCTANCE 0.82 μ H. SECONDARY: 3 T, NUMBER 22 ENAMEL WIRE WOUND ON COLD END OF PRIMARY

C_1, C_2 - 0.8 - 10 pF, AIR VARIABLE, (JOHANSEN 2950 OR EQUIVALENT) BYPASS AND FEEDTHROUGH CAPACITOR ARE 1000 pF CERAMIC (ALLEN-BRADLEY FASC OR EQUIVALENT)

*See Note 8

60 MHz I.F. AMPLIFIER WITH MANUAL GAIN CONTROL



CENTER FREQUENCY: 60 MHz

3 dB BANDWIDTH: 10.5 MHz

SPOT NOISE FIGURE: 1.8 ± 0.1 dB

GAIN: 62 dB

AGC RANGE: 60 dB

SUPPLY CURRENT: 15 mA; 21 mA @ 60 dB AGC

L_1 - 15 TURNS NUMBER 30 ENAMEL WIRE, CENTER TAPPED, WOUND ON 0.156" I.D. TOROID (MICROMETALS T30-13 OR EQUIVALENT) INDUCTANCE 0.32 μ H

T_1 - PRIMARY 14 TURNS NUMBER 24 ENAMEL WIRE SPACED EVENLY AROUND 0.156" I.D. TOROID (ARNOLD A4-310-125 SF OR EQUIVALENT) INDUCTANCE 0.82 μ H SECONDARY: 1 TURN, NEUTRALIZATION WINDING: 1 TURN

T_2 - AS T_1 WITHOUT NEUTRALIZATION WINDING

T_3 - PRIMARY: SAME AS T_1 , SECONDARY: 3 TURNS

C_1, C_2, C_3, C_4, C_5 - 0.8 to 10 pF AIR VARIABLE (JOHANSEN 2950 OR EQUIVALENT)

Q_1, Q_2, Q_3 - 2N4134 OR 2N4135

NEUTRALIZATION TECHNIQUE: APPLY 60 MHz SIGNAL TO AMPLIFIER INPUT. DISCONNECT EMITTER RESISTOR OF Q_1 . ADJUST C_3 FOR MINIMUM FEEDTHROUGH POWER. GAIN LOSS WITH ZERO EMITTER CURRENT IN Q_1 SHOULD BE GREATER THAN 45 dB.

BYPASS AND FEEDTHROUGH CAPACITORS ARE 1000 pF CERAMIC (ALLEN-BRADLEY FASC OR EQUIVALENT).

2N4137

NPN HIGH-SPEED SATURATED SWITCH

DIFFUSED SILICON PLANAR EPITAXIAL TRANSISTOR

FEATURES

- HIGH FREQUENCY CURRENT GAIN -- $f_T = 500$ MHz Min.
- HIGH VOLTAGE -- $V_{CE0} = 20$ VOLT Min.
- LOW CAPACITY -- $C_{obo} = 4.0$ pf Max.
- LOW CHARGE STORAGE TIME -- $\tau_s = 13$ ns Max.

ABSOLUTE MAXIMUM RATINGS [Note 1]

Maximum Temperatures	
Storage Temperature	-65°C to +200°C
Operating Temperature	200°C Maximum
Lead Temperature (Soldering, 60 sec Time Limit)	300°C Maximum
Maximum Power Dissipation	
Total Dissipation at 25°C Case Temperature	1.2 Watts
[Notes 2 and 3]	
at 100°C Case Temperature	0.68 Watt
[Notes 2 and 3]	
at 25°C Ambient Temperature	0.36 Watt
[Notes 2 and 3]	
Maximum Voltages and Currents	
V_{CBO} Collector to Base Voltage	40 Volts
V_{CES} Collector to Emitter Voltage	40 Volts
V_{CEO} Collector to Emitter Voltage [Note 4]	20 Volts
V_{EBO} Emitter to Base Voltage	4.5 Volts
I_C Collector Current (10 μ sec Pulse)	500 mA
I_C DC Collector Current	200 mA

-65°C to +200°C
200°C Maximum
300°C Maximum

1.2 Watts

0.68 Watt

0.36 Watt

40 Volts

40 Volts

20 Volts

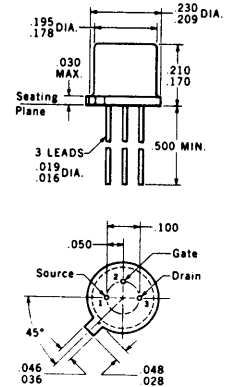
4.5 Volts

500 mA

200 mA

PHYSICAL DIMENSIONS

in accordance with
JEDEC (TO-18) outline



NOTES: All dimensions in inches.
Leads are gold plated brass.
Gate internally connected to case.
Package weight is 0.43 gram.

ELECTRICAL CHARACTERISTICS (25°C Free Air Temperature unless otherwise noted)

SYMBOL	CHARACTERISTIC	MIN.	TYP.	MAX.	UNITS	TEST CONDITIONS
h_{FE}	DC Pulse Current Gain [Note 5]	40	66	120		$I_C = 10$ mA $V_{CE} = 1.0$ V
$h_{FE} (-55^\circ\text{C})$	DC Pulse Current Gain [Note 5]	20	50			$I_C = 10$ mA $V_{CE} = 0.35$ V
$V_{BE} (\text{sat})$	Pulsed Base Saturation Voltage [Note 5]	0.72	0.8	0.85	Volts	$I_C = 10$ mA $I_B = 1.0$ mA
$V_{BE} (\text{sat})$	Pulsed Base Saturation Voltage (-55°C to +125°C)	0.59		1.02	Volts	$I_C = 10$ mA $I_B = 1.0$ mA
	[Note 5]					
$V_{BE} (\text{sat})$	Pulsed Base Saturation Voltage [Note 5]		0.9	1.15	Volts	$I_C = 30$ mA $I_B = 3.0$ mA
$V_{BE} (\text{sat})$	Pulsed Base Saturation Voltage [Note 5]		1.1	1.6	Volts	$I_C = 100$ mA $I_B = 10$ mA
$V_{CE} (\text{sat})$	Pulse Collector Saturation Voltage (125°C) [Note 5]	0.19	0.3		Volts	$I_C = 10$ mA $I_B = 1.0$ mA
I_{CES}	Collector Reverse Current	0.05	0.4		μ A	$V_{BE} = 0$ $V_{CE} = 20$ V
$I_{CBO} (150^\circ\text{C})$	Collector Cutoff Current		10	30	μ A	$I_E = 0$ $V_{CE} = 20$ V
BV_{CES}	Collector to Emitter Breakdown Voltage	40			Volts	$I_C = 10$ μ A $V_{BE} = 0$
BV_{CBO}	Collector to Base Breakdown Voltage	40			Volts	$I_C = 10$ μ A $I_E = 0$
$V_{CEO} (\text{sust})$	Collector to Emitter Sustaining Voltage	20			Volts	$I_C = 10$ mA $I_B = 0$
	[Notes 4 and 5]					(pulsed)
BV_{EBO}	Emitter to Base Breakdown Voltage	4.5			Volts	$I_E = 10$ μ A $I_C = 0$

NOTES:

- (1) These ratings are limiting values above which the serviceability of any individual semiconductor device may be impaired.
- (2) These are steady state limits. The factory should be consulted on applications involving pulsed or low duty cycle operations.
- (3) These ratings give a maximum junction temperature of 200°C and junction-to-case thermal resistance of 146°C/watt (derating factor of 6.85 mW/°C). Junction-to-ambient thermal resistance of 486°C/watt (derating factor of 2.06 mW/°C).
- (4) Ratings refer to a high-current point where collector-to-emitter voltage is lowest.
- (5) Pulse Conditions: length = 300 μ sec; duty cycle = 1%.
- (6) See switching circuits for exact value of I_C , I_{B1} , and I_{B2} .

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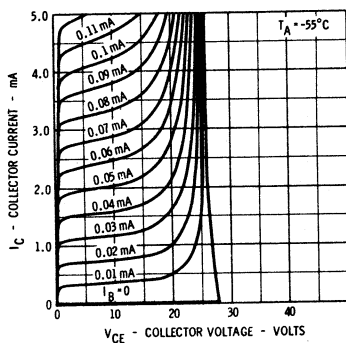
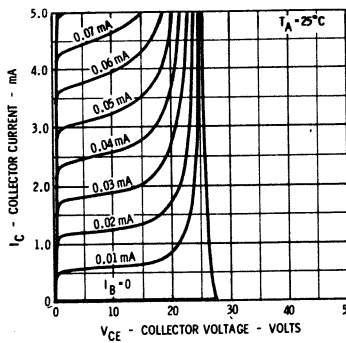
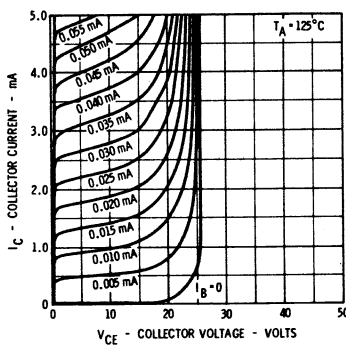
FAIRCHILD TRANSISTOR 2N4137

ELECTRICAL CHARACTERISTICS (25°C Free Air Temperature unless otherwise noted)

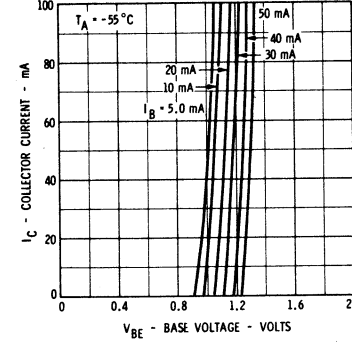
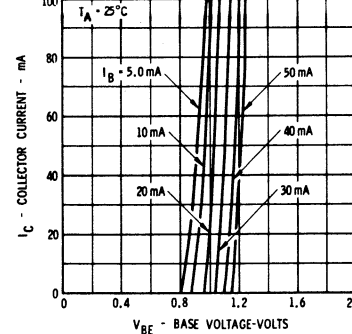
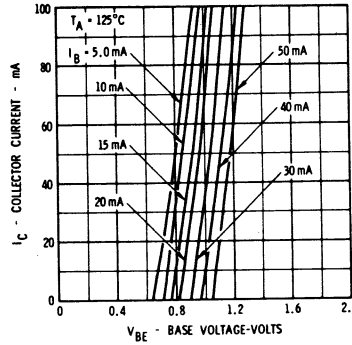
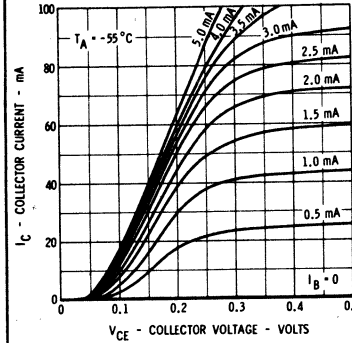
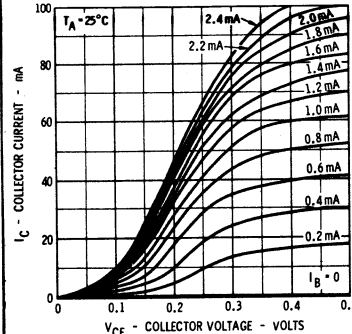
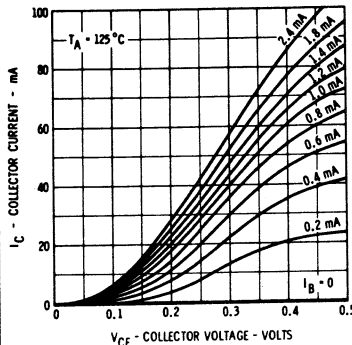
SYMBOL	CHARACTERISTIC	MIN.	TYP.	MAX.	UNITS	TEST CONDITIONS
h_{FE}	DC Pulse Current Gain [Note 5]	40	63	120		$I_C = 10 \text{ mA}$ $V_{CE} = 0.35 \text{ V}$
h_{FE}	DC Pulse Current Gain [Note 5]	30	71			$I_C = 30 \text{ mA}$ $V_{CE} = 0.4 \text{ V}$
h_{FE}	DC Pulse Current Gain [Note 5]	20				$I_C = 100 \text{ mA}$ $V_{CE} = 1.0 \text{ V}$
$V_{CE(sat)}$	Pulsed Collector Saturation Voltage [Note 5]		0.14	0.2	Volts	$I_C = 10 \text{ mA}$ $I_B = 1.0 \text{ mA}$
$V_{CE(sat)}$	Pulsed Collector Saturation Voltage [Note 5]		0.12	0.18	Volts	$I_C = 10 \text{ mA}$ $I_B = 3.3 \text{ mA}$
$V_{CE(sat)}$	Pulsed Collector Saturation Voltage [Note 5]		0.17	0.25	Volts	$I_C = 30 \text{ mA}$ $I_B = 3.0 \text{ mA}$
$V_{CE(sat)}$	Pulsed Collector Saturation Voltage [Note 5]		0.28	0.5	Volts	$I_C = 100 \text{ mA}$ $I_B = 10 \text{ mA}$
$V_{BE(sat)}$	Pulsed Base Saturation Voltage [Note 5]	0.74	0.85	1.0	Volts	$I_C = 10 \text{ mA}$ $I_B = 3.3 \text{ mA}$
h_{fe}	High Frequency Current Gain ($f = 100 \text{ mc}$)	5.0	6.75			$I_C = 10 \text{ mA}$ $V_{CE} = 10 \text{ V}$
C_{os}	Output Capacitance		2.3	4.0	pf	$I_E = 0$ $V_{CE} = 5.0 \text{ V}$
τ_s	Charge Storage Time Constant [Note 6]		6.0	13	nsec	$I_C = I_{B1} \approx 10 \text{ mA}$ $I_{B2} \approx -10 \text{ mA}$
t_{on}	Turn On Time [Note 6]		9.0	12	nsec	$I_C \approx 10 \text{ mA}$ $I_{B1} \approx 3.3 \text{ mA}$
t_{off}	Turn Off Time [Note 6]		7.0	12	nsec	$I_C \approx 10 \text{ mA}$ $I_{B1} \approx 3.3 \text{ mA}$ $I_{B2} \approx -3.3 \text{ mA}$

TYPICAL COLLECTOR AND BASE CHARACTERISTICS

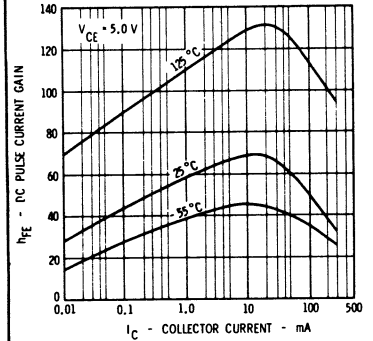
ACTIVE REGION



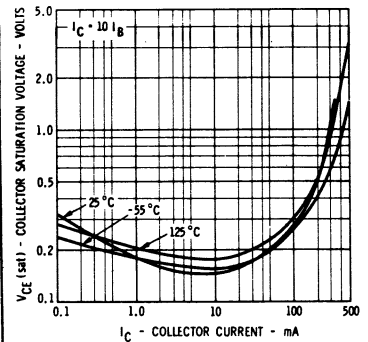
SATURATION REGION



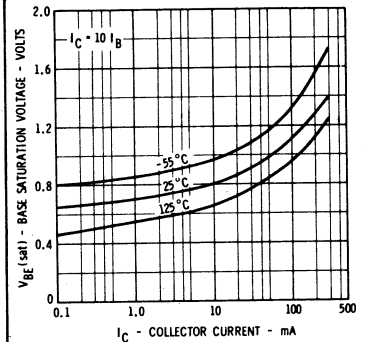
PULSED DC CURRENT GAIN VERSUS COLLECTOR CURRENT



COLLECTOR SATURATION VOLTAGE VERSUS COLLECTOR CURRENT



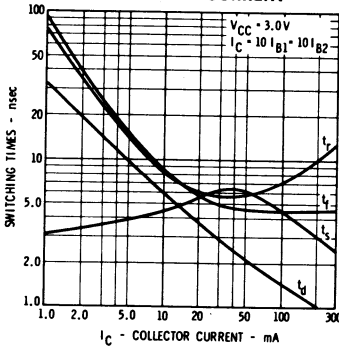
BASE SATURATION VOLTAGE VERSUS COLLECTOR CURRENT



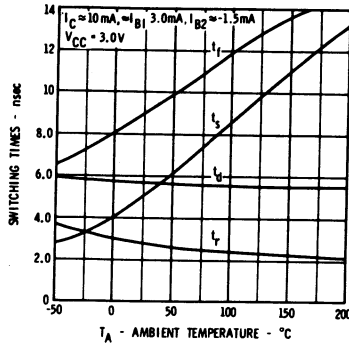
FAIRCHILD TRANSISTOR 2N4137

TYPICAL ELECTRICAL CHARACTERISTICS

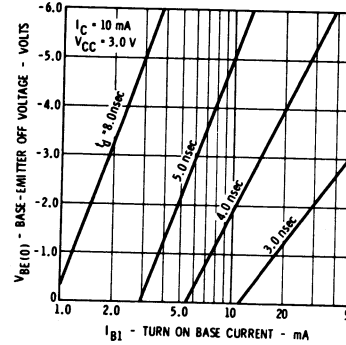
SWITCHING TIMES VERSUS COLLECTOR CURRENT



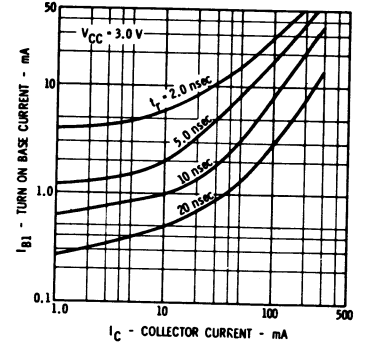
SWITCHING TIMES VERSUS AMBIENT TEMPERATURE



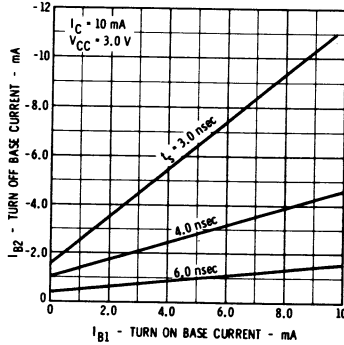
DELAY TIME VERSUS BASE-EMITTER OFF VOLTAGE AND TURN ON BASE CURRENT



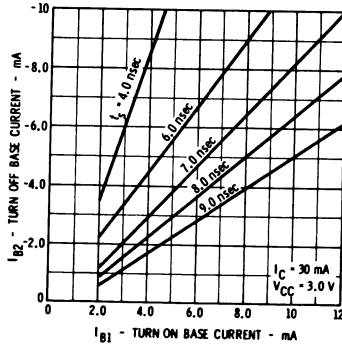
RISE TIME VERSUS TURN ON BASE CURRENT AND COLLECTOR CURRENT



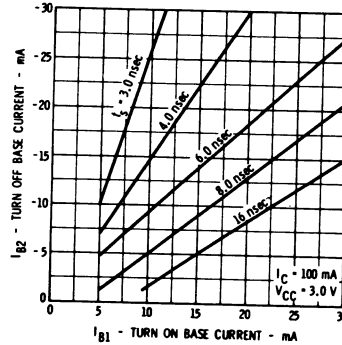
STORAGE TIME VERSUS TURN ON AND TURN OFF BASE CURRENTS



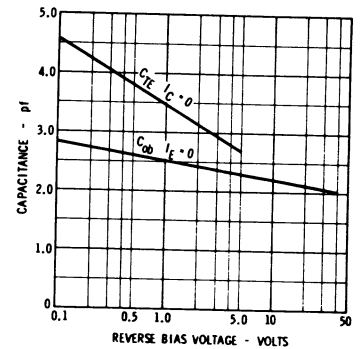
STORAGE TIME VERSUS TURN ON AND TURN OFF BASE CURRENTS



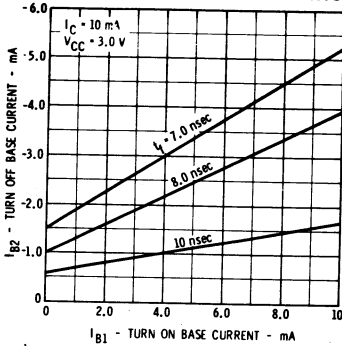
STORAGE TIME VERSUS TURN ON AND TURN OFF BASE CURRENTS



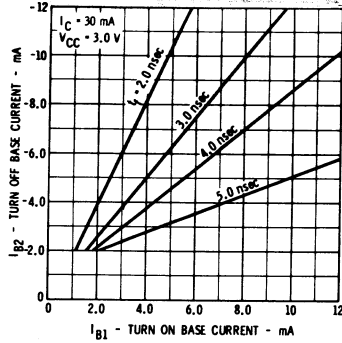
EMITTER TRANSITION AND OUTPUT CAPACITANCES VERSUS REVERSE BIAS VOLTAGE



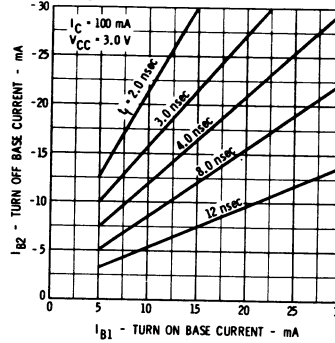
FALL TIME VERSUS TURN ON AND TURN OFF BASE CURRENTS



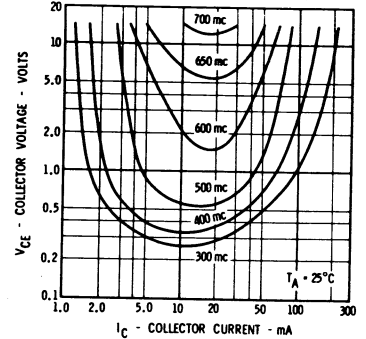
FALL TIME VERSUS TURN ON AND TURN OFF BASE CURRENTS



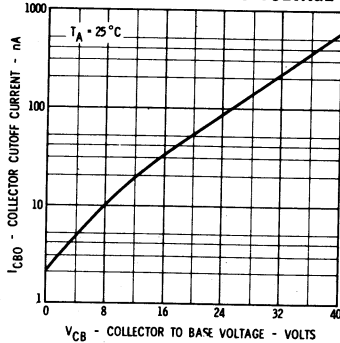
FALL TIME VERSUS TURN ON AND TURN OFF BASE CURRENTS



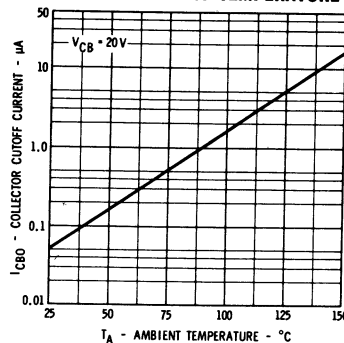
CONTOURS OF CONSTANT GAIN BANDWIDTH PRODUCT (f_T)



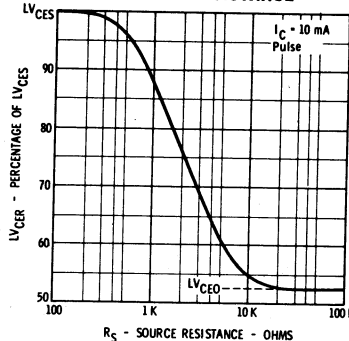
COLLECTOR CUTOFF CURRENT VERSUS REVERSE BIAS VOLTAGE



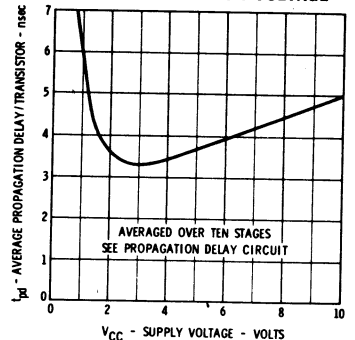
COLLECTOR CUTOFF CURRENT VERSUS AMBIENT TEMPERATURE



LOWER LIMITING VOLTAGE VERSUS SOURCE RESISTANCE

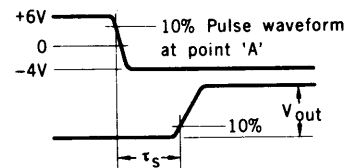
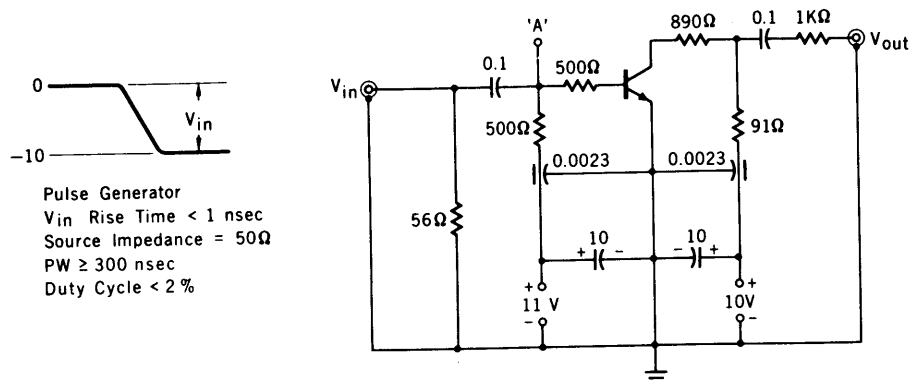


AVERAGE PROPAGATION DELAY PER TRANSISTOR VERSUS SUPPLY VOLTAGE



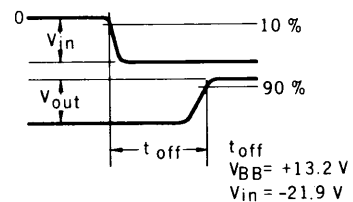
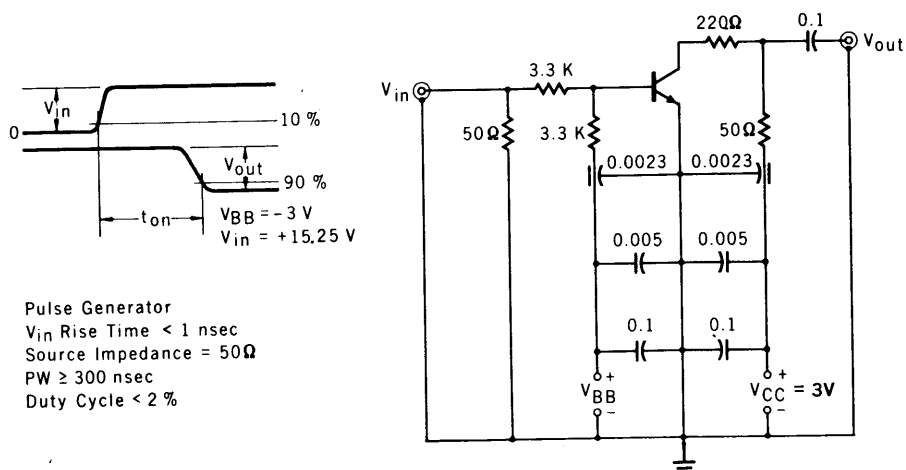
FAIRCHILD TRANSISTOR 2N4137

CHARGE STORAGE TIME MEASUREMENT CIRCUIT



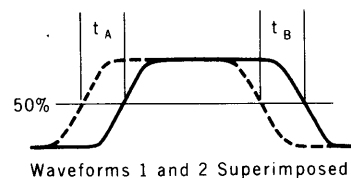
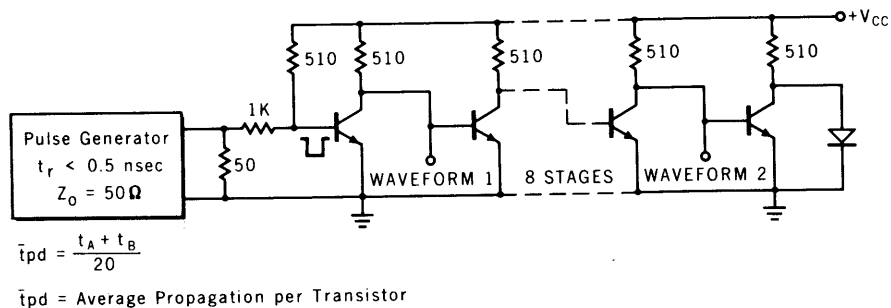
To Sampling Oscilloscope
 Input Impedance = 50Ω
 Rise Time ≤ 1 nsec

$t_{ON} - t_{OFF}$ MEASUREMENT CIRCUIT



To Sampling Oscilloscope
 Input Impedance = 50Ω
 Rise Time ≤ 1 nsec

CIRCUIT FOR MEASUREMENT OF PROPAGATION DELAY



2N4212 THROUGH 2N4218

PNPN SILICON CONTROLLED RECTIFIERS

DIFFUSED SILICON PLANAR* THYRISTORS

- FORWARD CURRENT RATING OF 1.25 AMPS D.C. AT $T_C = 85^\circ\text{C}$
- BLOCKING VOLTAGE CAPABILITY THROUGH 300 VOLTS
- MAXIMUM GATE TRIGGER CURRENT OF 100 μA AT $T_C = 25^\circ\text{C}$
- RELIABLE PLANAR* CONSTRUCTION

ABSOLUTE MAXIMUM RATINGS (Note 1)

Maximum Temperatures

- †Storage Temperature
- †Operating Junction Temperature

Maximum Currents

- rms Forward Current $T_C = 85^\circ\text{C}$
- (180° Conduction Angle) (Note 2) $T_A = 25^\circ\text{C}$
- Continuous Forward Current $T_C = 85^\circ\text{C}$
- $T_A = 25^\circ\text{C}$
- Average Forward Current $\dagger T_C = 85^\circ\text{C}$
- (180° Conduction Angle) (Note 2) $\dagger T_C = 105^\circ\text{C}$
- $T_A = 25^\circ\text{C}$
- $T_C = 85^\circ\text{C}$
- †Surge Current
- (1/2 cycle sine wave, 60 Hz peak)
- †Peak Forward Gate Current
- (180° Conduction Angle) $T_C = 25^\circ$

Maximum Gate Power ($T_C = 85^\circ\text{C}$)

- †Peak Gate Power Dissipation
- †Average Gate Power Dissipation

Maximum Voltages ($T_C = -65^\circ\text{C}$ to 125°C)

- †Peak Reverse Gate Voltage
- †Peak Forward and Reverse Blocking Voltages

- T_{stg} -65°C to $+150^\circ\text{C}$
- T_J -65°C to $+125^\circ\text{C}$

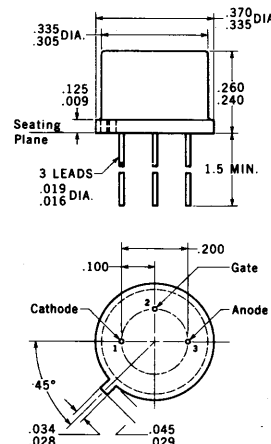
- $I_{F(rms)}$ 1.6 Amps
- 490 mA
- $I_{F(DC)}$ 1.25 Amps
- 355 mA
- $I_{F(AV)}$ 1.0 Amp
- 0.5 Amp
- 310 mA
- $I_{FM(surge)}$ 15 Amps
- I_{GFM} 0.1 Amp

- P_{GM} 0.1 Watt
- $P_{GM(AV)}$ 0.01 Watt

- V_{GRM} 6.0 Volts
- V_{FM}, V_{RM} 2N4212 25 Volts
- 2N4213 50 Volts
- 2N4214 100 Volts
- 2N4215 150 Volts
- 2N4216 200 Volts
- 2N4217 250 Volts
- 2N4218 300 Volts

PHYSICAL DIMENSIONS

in accordance with
JEDEC (TO-5) outline



NOTES:

- All dimensions in inches.
- Leads are gold-plated Kovar.
- Anode internally connected to case.
- Package weight is 1.23 grams

ELECTRICAL CHARACTERISTICS (25°C Case Temperature unless otherwise noted)

SYMBOL	CHARACTERISTIC	MIN.	TYP.	MAX.	UNITS	TEST CONDITIONS
I_{FX}	Forward Blocking Current		40	200	nA	$V_{AK} = \text{Rated } V_{FM}$ $R_{GK} = 1.0 \text{ k}\Omega$
$\dagger I_{FX}(125^\circ\text{C})$	Forward Blocking Current		20	200	μA	$V_{AK} = \text{Rated } V_{FM}$ $R_{GK} = 1.0 \text{ k}\Omega$
I_{RX}	Reverse Blocking Current		40	200	nA	$V_{AK} = \text{Rated } V_{RM}$ $R_{GK} = 1.0 \text{ k}\Omega$
$\dagger I_{RX}(125^\circ\text{C})$	Reverse Blocking Current		20	200	μA	$V_{AK} = \text{Rated } V_{RM}$ $R_{GK} = 1.0 \text{ k}\Omega$
I_{GT}	Gate Trigger Current		40	100	μA	$V_{AA} = 7.0 \text{ V}$ $R_L = 100 \Omega$
$\dagger I_{GT}(-65^\circ\text{C})$	Gate Trigger Current		120	300	μA	$V_{AA} = 7.0 \text{ V}$ $R_L = 100 \Omega$
V_{GT}	Gate Trigger Voltage		0.58	0.7	Volt	$V_{AA} = 7.0 \text{ V}$, $R_{GK} = 1.0 \text{ k}\Omega$, $R_L = 100 \Omega$
$\dagger V_{GT}(-65^\circ\text{C})$	Gate Trigger Voltage		0.8	1.0	Volt	$V_{AA} = 7.0 \text{ V}$, $R_{GK} = 1.0 \text{ k}\Omega$, $R_L = 100 \Omega$
$\dagger V_{GT}(125^\circ\text{C})$	Gate Trigger Voltage	0.1	0.21		Volt	$V_{AA} = \text{Rated } V_{FM}$, $R_{GK} = 1.0 \text{ k}\Omega$, $R_L = 100 \Omega$
I_{HX}	Holding Current		0.9		mA	$V_{AA} = 7.0 \text{ V}$ $R_{GK} = 1.0 \text{ k}\Omega$
$\dagger I_{HX}(-65^\circ\text{C})$	Holding Current		1.75	7.0	mA	$V_{AA} = 7.0 \text{ V}$ $R_{GK} = 1.0 \text{ k}\Omega$
I_{GR}	Reverse Gate Current		.005	1.0	μA	$V_{GK} = -6.0 \text{ V}$ $I_A = 0$
$\dagger V_F$	On Voltage (Note 4)		1.7	2.0	Volts	$I_F = 3.14 \text{ A}$
dV/dt	Critical Rate of Rise of Anode Voltage		150		V/ μs	$V_{AA} = \text{Rated } V_{FM}$ $R_{GK} = 500 \Omega$

†JEDEC Registered Values.

*Planar is a patented Fairchild process.

NOTES:

- (1) These ratings are limiting values above which the reliability of the device may be impaired.
- (2) These ratings give a maximum junction temperature of 125°C with the maximum average power dissipation and a maximum junction to case thermal resistance of 18°C/Watt and a junction to ambient thermal resistance of 225°C/Watt .
- (3) Ambient temperature derating curves are derived with no external heat sink connected.
- (4) Pulse Conditions: length = 1ms max; duty cycle $\leq 1\%$.

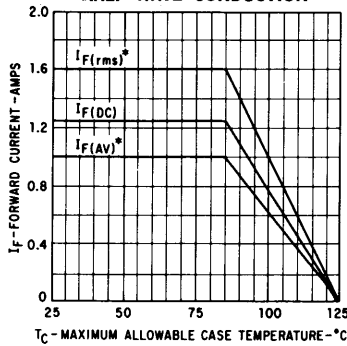
FAIRCHILD
SEMICONDUCTOR
A DIVISION OF FAIRCHILD CAMERA AND INSTRUMENT CORPORATION

313 FAIRCHILD DRIVE, MOUNTAIN VIEW, CALIFORNIA, (415) 962-5011, TWX: 910-379-6435

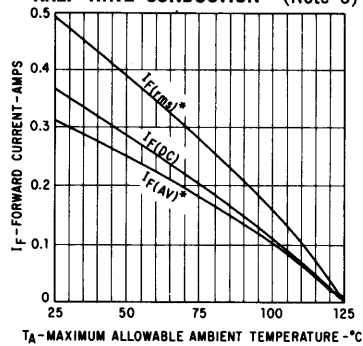
FAIRCHILD THYRISTORS 2N4212 through 2N4218

MAXIMUM RATINGS

FORWARD CURRENT VERSUS MAXIMUM ALLOWABLE CASE TEMPERATURE
HALF WAVE CONDUCTION*



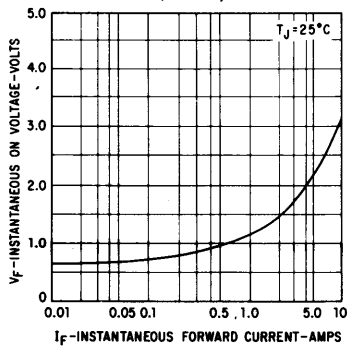
FORWARD CURRENT VERSUS MAXIMUM ALLOWABLE AMBIENT TEMPERATURE
HALF WAVE CONDUCTION* (Note 3)



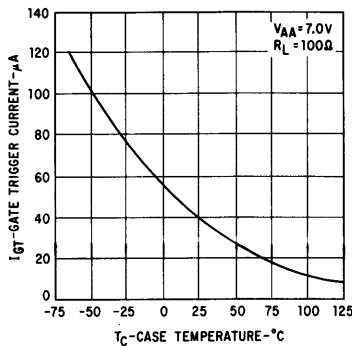
*180° Conduction Angle for Sinusoidal Current Waveform; 50 to 400 Hz.

TYPICAL ELECTRICAL CHARACTERISTICS

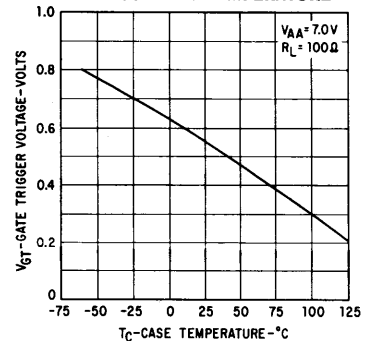
INSTANTANEOUS ON VOLTAGE
VERSUS FORWARD CURRENT
(Note 4)



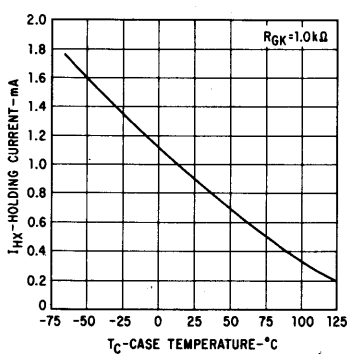
GATE TRIGGER CURRENT
VERSUS CASE TEMPERATURE



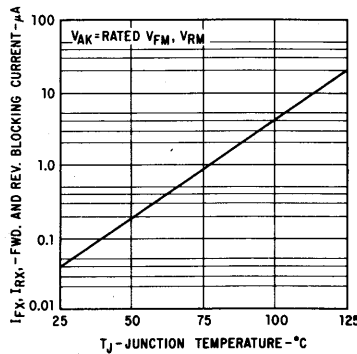
GATE TRIGGER VOLTAGE
VERSUS CASE TEMPERATURE



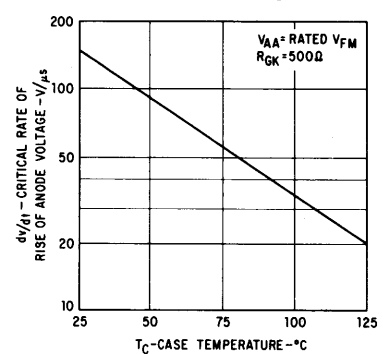
HOLDING CURRENT VERSUS
CASE TEMPERATURE



FORWARD AND REVERSE
BLOCKING CURRENT VERSUS
JUNCTION TEMPERATURE



ALLOWABLE CRITICAL RATE OF
RISE OF ANODE VOLTAGE VERSUS
CASE TEMPERATURE



2N4251

NPN RADIATION RESISTANT SWITCH

DIFFUSED SILICON PLANAR* EPITAXIAL TRANSISTOR

FEATURES

- HIGH FREQUENCY — $f_T = 1.3$ GHz Min.
- HIGH h_{FE} @ $I_C = 10$ mA — 100 Min., 180 Typ., 300 Max.
- LOW $V_{CE(sat)}$ @ $I_C = 10$ mA — 50 mV Typ., 150 mV Max.
- LOW C_{obo} @ $V_{CB} = 10$ V — 2.0 pF Max.
- LOW C_{ibo} @ $V_{EB} = 0.5$ V — 4.0 pF Max.
- GUARANTEED PERFORMANCE AFTER FAST NEUTRON DOSE (10^{15} nvt)

ABSOLUTE MAXIMUM RATINGS

Maximum Temperatures (Note 1)

Storage Temperature
Operating Junction Temperature
Lead Temperature (Soldering, 10 seconds Time Limit)

−55°C to +200°C
+200°C Maximum
+300°C Maximum

Maximum Voltages (Note 1)

V_{CBO} Collector to Base Voltage
 V_{CEO} Collector to Emitter Voltage
 V_{EBO} Emitter to Base Voltage

15 Volts
10 Volts
4.5 Volts

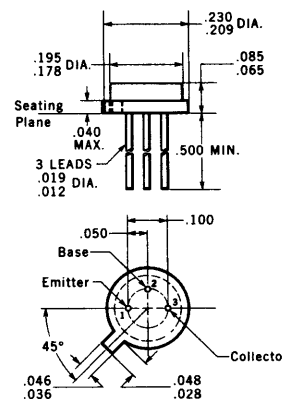
Maximum Power Dissipation (Note 2 and 3)

Total Dissipation at
25°C Case Temperature
25°C Ambient Temperature

1.3 Watts
0.25 Watt

PHYSICAL DIMENSIONS

in accordance with
JEDEC (TO-46) outline



NOTES: All dimensions in inches
Leads are gold-plated lower
Collector internally connected to case
Package weight is 0.36 gram

ELECTRICAL CHARACTERISTICS (25°C Free Air Temperature unless otherwise noted)

SYMBOL	CHARACTERISTICS	PRE-IRRADIATION			POST-IRRADIATION			UNITS	TEST CONDITIONS	
		MIN.	TYP.	MAX.	MIN.	TYP.	MAX.			
$V_{CE(sust)}$	Collector to Emitter Sustaining Voltage (Note 4 and 6)	10	12		10	20		Volts	$I_C = 10$ mA (pulsed)	$I_B = 0$
BV_{CES}	Collector to Emitter Breakdown Voltage	15	23		15	25		Volts	$I_C = 1.0$ mA	$I_B = 0$
BV_{EBO}	Emitter to Base Breakdown Voltage	4.5	5.5		4.5	5.6		Volts	$I_C = 0$	$I_E = 1.0$ mA
h_{FE}	DC Pulse Current Gain (Note 4)	32	78		5.0	7.0			$I_C = 100$ μ A	$V_{CE} = 5.0$ V
h_{FE}	DC Pulse Current Gain (Note 4)	62	124		9.0	12			$I_C = 1.0$ mA	$V_{CE} = 5.0$ V
h_{FE}	DC Pulse Current Gain (Note 4)	100	180	300	15	20			$I_C = 10$ mA	$V_{CE} = 5.0$ V
h_{FE}	DC Pulse Current Gain (Note 4)	94	170		14	17			$I_C = 100$ mA	$V_{CE} = 5.0$ V
$h_{FE} (-55^\circ\text{C})$	DC Pulse Current Gain (Note 4)	50	90		8.0	12			$I_C = 10$ mA	$V_{CE} = 5.0$ V
$V_{CE(sat)}$	Pulsed Collector Saturation Voltage (Note 4)		0.05	0.15		0.18	0.25	Volts	$I_C = 10$ mA	$I_B = 1.0$ mA
$V_{BE(sat)}$	Pulsed Base Saturation Voltage (Note 4)		0.80	0.90		0.80	0.90	Volts	$I_C = 10$ mA	$I_B = 1.0$ mA
h_{fe}	High Frequency Current Gain ($f = 100$ MHz)	13	15		10	13			$I_C = 10$ mA	$V_{CE} = 5.0$ V
C_{obo}	Common Base, Open Circuit Output Capacitance			2.0			2.0	pF	$I_E = 0$	$V_{CB} = 10$ V
C_{ibo}	Common Base, Open Circuit Input Capacitance			4.0			4.0	pF	$I_C = 0$	$V_{EB} = 0.5$ V
I_{CBO}	Collector Cutoff Current		0.005	1.0		0.1	10.0	μ A	$I_E = 0$	$V_{CB} = 10$ V
$I_{CBO} (150^\circ\text{C})$	Collector Cutoff Current			10			10	μ A	$I_E = 0$	$V_{CB} = 10$ V
t_{on}	Turn On Time (see Figure 1)		13	20		13	20	ns	$I_C = 10$ mA	$I_{B1} = 1.0$ mA
t_{off}	Turn Off Time (see Figure 1)		49	60		5.0	60	ns	$I_C = 10$ mA	$I_{B1} = 1.0$ mA $I_{B2} = 1.0$ mA
τ_s	Charge Storage Time (see Figure 2)		60	80		4.0	80	ns	$I_C = 10$ mA	$I_{B1} = 10$ mA $I_{B2} = 10$ mA

* Planar is a patented Fairchild process.

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TYPICAL ELECTRICAL CHARACTERISTICS

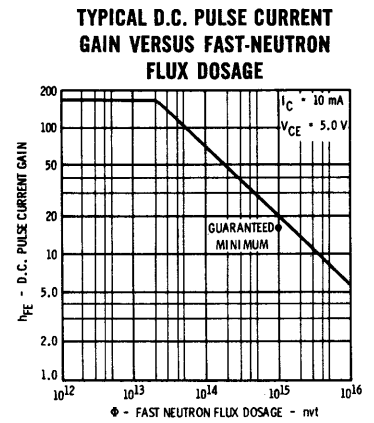
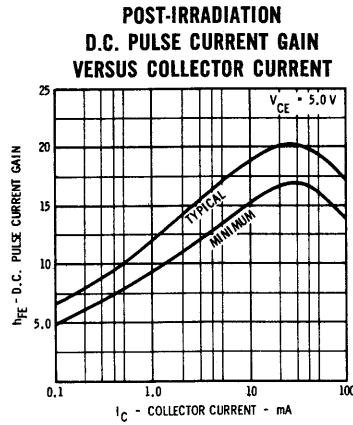
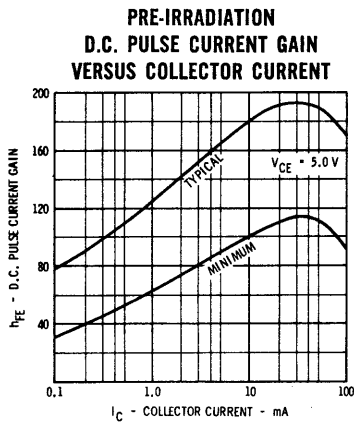
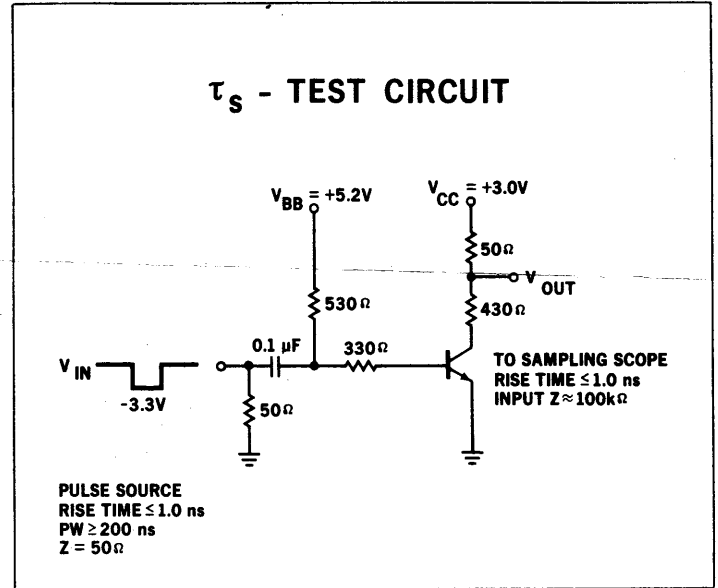
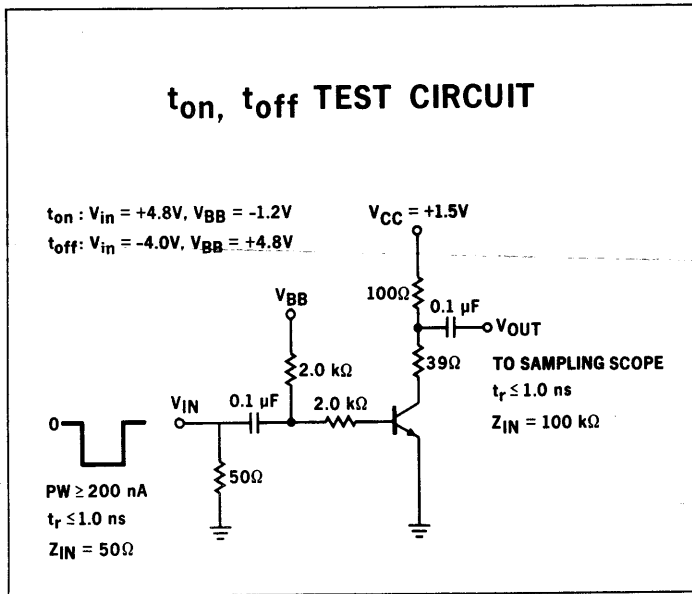


FIGURE 1

FIGURE 2



NOTES:

- (1) These ratings are limiting values above which the serviceability of any individual semiconductor device may be impaired.
- (2) These are steady state limits. The factory should be consulted on applications involving pulsed or low duty cycle operations.
- (3) These ratings based on maximum junction temperature of 200°C and junction to case thermal resistance of 135°C/watt (derating factor of 7.43 mW/°C) and junction to ambient thermal resistance of 700°C/watt (derating factor of 1.43 mW/°C).
- (4) Pulse conditions: length = 300 μ s; duty cycle = 1%.
- (5) Post-irradiation characteristics after an integrated fast (>100 KEV) neutron flux of 10^{15} nvt (neutrons per cm²).
- (6) This rating refers to a high-current point where collector to emitter voltage is lowest.

2N4359

PNP LOW-NOISE, LOW-LEVEL AMPLIFIER

DIFFUSED SILICON PLANAR* TRANSISTOR

- **LOW NOISE** $NF = 4.0 \text{ dB (MAX) AT } 1.0 \text{ kHz}$
- **HIGH BETA** $h_{FE} = 50\text{-}500 \text{ AT } 10 \mu\text{A}$
- **EXCELLENT BETA LINEARITY** **FROM $10 \mu\text{A}$ TO 50 mA**
- **HIGH BREAKDOWN VOLTAGE** $LV_{CEO} = 45 \text{ VOLTS (MIN)}$

ABSOLUTE MAXIMUM RATINGS (Note 1)

Maximum Temperatures

Storage Temperature	-65°C to $+200^{\circ}\text{C}$
Operating Junction Temperature	200°C
Lead Temperature (Soldering, 60 Sec. Time Limit)	300°C

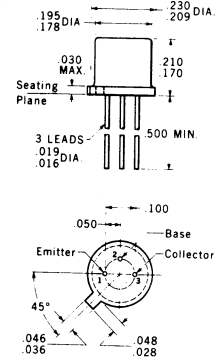
Maximum Power Dissipation

Total Dissipation at 25°C Case Temperature (Notes 2 and 3)	1.2 Watts
at 25°C Ambient Temperature (Notes 2 and 3)	0.36 Watt

Maximum Voltages

V_{CBO} Collector to Base Voltage	-45 Volts
V_{CEO} Collector to Emitter Voltage (Note 4)	-45 Volts
V_{EBO} Emitter to Base Voltage	-5.0 Volts

PHYSICAL DIMENSIONS in accordance with JEDEC (TO-18) outline



NOTES: All dimensions in inches
Leads are gold-plated lower
Collector internally connected to case
Package weight is 0.43 gram

ELECTRICAL CHARACTERISTICS (25°C Free Air Temperature Unless Otherwise Noted)

SYMBOL	CHARACTERISTIC	MIN.	TYP.	MAX.	UNITS	TEST CONDITIONS
h_{FE}	DC Current Gain	50	210	500		$I_C = 10 \mu\text{A}$ $V_{CE} = -5.0 \text{ V}$
h_{FE}	DC Current Gain	50	260			$I_C = 100 \mu\text{A}$ $V_{CE} = -5.0 \text{ V}$
h_{FE}	DC Current Gain	50	310	600		$I_C = 1.0 \text{ mA}$ $V_{CE} = -5.0 \text{ V}$
h_{FE}	DC Pulse Current Gain (Note 5)	50	340			$I_C = 10 \text{ mA}$ $V_{CE} = -5.0 \text{ V}$
$h_{FE} (0^{\circ}\text{C})$	DC Current Gain	35	160			$I_C = 10 \mu\text{A}$ $V_{CE} = -5.0 \text{ V}$
$V_{CEO} (\text{sust})$	Collector to Emitter Sustaining Voltage	-45			Volts	$I_B = 0$
h_{FE}	High Frequency Current Gain ($f = 20 \text{ MHz}$)	1.0	6.0	10		$I_C = 1.0 \text{ mA}$ $V_{CE} = -5.0 \text{ V}$
NF	Wide Band Noise Figure ($f = 10 \text{ Hz to } 10 \text{ kHz}$)		1.7	5.0	dB	$I_C = 20 \mu\text{A}$ $V_{CE} = -5.0 \text{ V}$
NF	Narrow Band Noise Figure ($f = 10 \text{ kHz}$)		1.0	3.0	dB	$R_S = 10 \text{ k}\Omega$ Power Bandwidth = 15.7 kHz
NF	Narrow Band Noise Figure ($f = 1.0 \text{ kHz}$)		1.5	4.0	dB	$I_C = 20 \mu\text{A}$ $V_{CE} = -5.0 \text{ V}$
BV_{CBO}	Collector to Base Breakdown Voltage	-45			Volts	$R_S = 10 \text{ k}\Omega$ Power Bandwidth = 150 Hz
BV_{EBO}	Emitter to Base Breakdown Voltage	-5.0			Volts	$I_C = 10 \mu\text{A}$ $I_E = 0$
I_{CBO}	Collector Reverse Current		0.35	10	nA	$I_C = 0$ $I_E = 100 \mu\text{A}$
I_{EBO}	Emitter Cutoff Current		2.0	20	nA	$I_C = 0$ $V_{CB} = -25 \text{ V}$
C_{obo}	Open Circuit Output Capacitance ($f = 1.0 \text{ MHz}$)		4.0	6.0	pF	$I_C = 0$ $V_{EB} = -3.0 \text{ V}$
C_{ibo}	Open Circuit Input Capacitance ($f = 1.0 \text{ MHz}$)		14	18	pF	$I_C = 0$ $V_{CB} = -5.0 \text{ V}$
$I_{CBO} (85^{\circ}\text{C})$	Collector Reverse Current		0.05	2.0	μA	$I_C = 0$ $V_{EB} = -0.5 \text{ V}$
$V_{CE} (\text{sat})$	Pulsed Collector Saturation Voltage (Note 5)	-0.13	-0.25		Volts	$I_C = 10 \text{ mA}$ $V_{CB} = -25 \text{ V}$
$V_{BE} (\text{sat})$	Pulsed Base Saturation Voltage (Note 5)	-0.76	-0.90		Volts	$I_C = 10 \text{ mA}$ $I_B = 1.0 \text{ mA}$

* Planar is a patented Fairchild process.

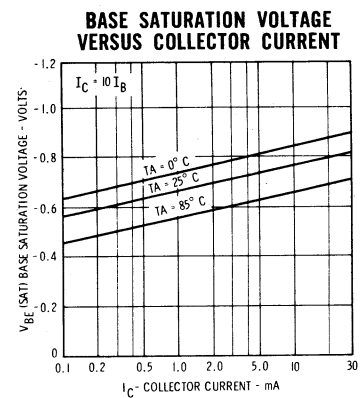
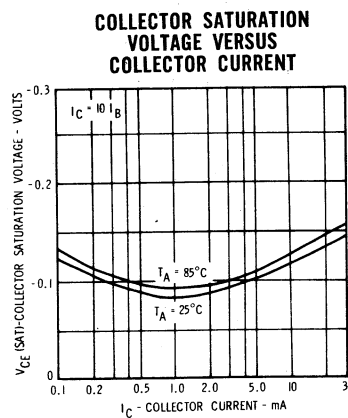
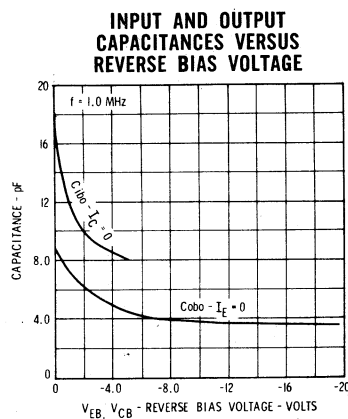
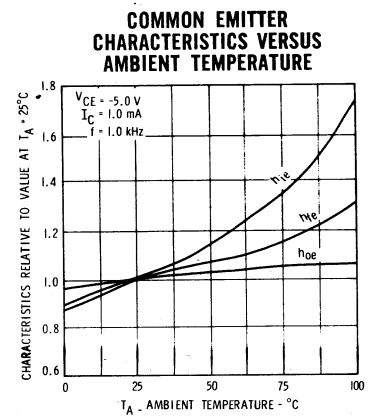
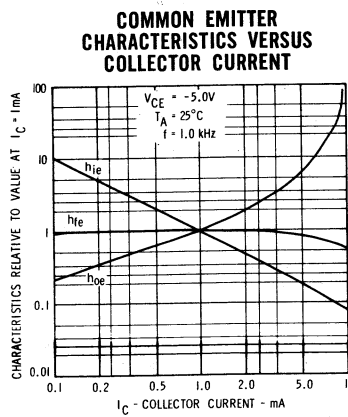
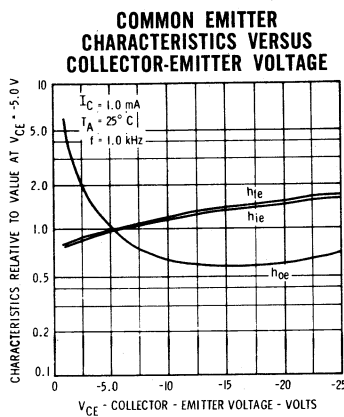
FAIRCHILD
SEMICONDUCTOR
A DIVISION OF FAIRCHILD CAMERA AND INSTRUMENT CORPORATION

FAIRCHILD TRANSISTOR 2N4359

SMALL SIGNAL CHARACTERISTICS (f = 1.0 kHz)

SYMBOL	CHARACTERISTICS	MIN.	MAX.	UNITS	TEST CONDITIONS
h_{fe}	Small Signal Current Gain	50	700		$I_C = 1.0 \text{ mA}$ $V_{CE} = -5.0 \text{ V}$
h_{ie}	Input Resistance	1.0	20	k ohms	$I_C = 1.0 \text{ mA}$ $V_{CE} = -5.0 \text{ V}$
h_{oe}	Output Conductance	5.0	60	μmhos	$I_C = 1.0 \text{ mA}$ $V_{CE} = -5.0 \text{ V}$
h_{re}	Voltage Feedback Ratio		10	$\times 10^{-4}$	$I_C = 1.0 \text{ mA}$ $V_{CE} = -5.0 \text{ V}$

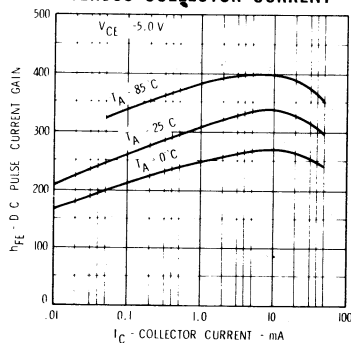
TYPICAL ELECTRICAL CHARACTERISTICS



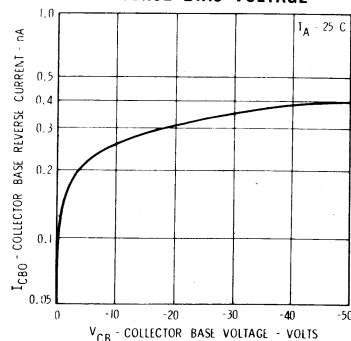
FAIRCHILD TRANSISTOR 2N4359

TYPICAL ELECTRICAL CHARACTERISTICS

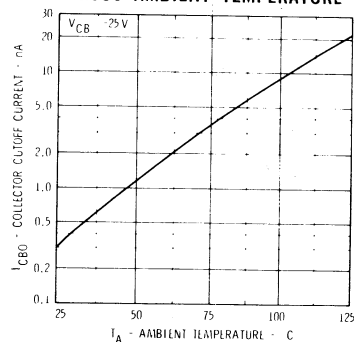
DC PULSE-CURRENT GAIN
VERSUS COLLECTOR CURRENT



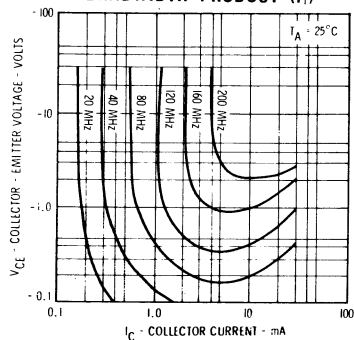
COLLECTOR-BASE DIODE
REVERSE CURRENT VERSUS
REVERSE BIAS VOLTAGE



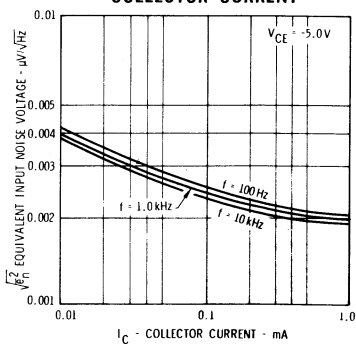
COLLECTOR CUTOFF CURRENT
VERSUS AMBIENT TEMPERATURE



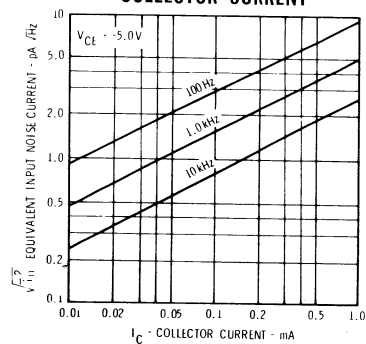
CONTOURS OF CONSTANT GAIN
BANDWIDTH PRODUCT (f_T)



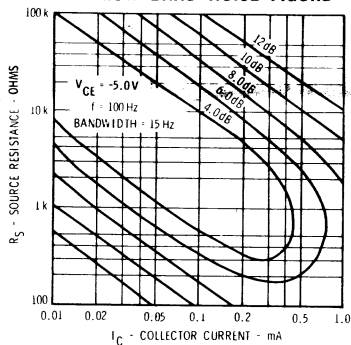
EQUIVALENT INPUT NOISE
VOLTAGE VERSUS
COLLECTOR CURRENT



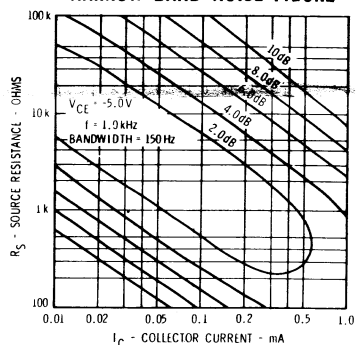
EQUIVALENT INPUT NOISE
CURRENT VERSUS
COLLECTOR CURRENT



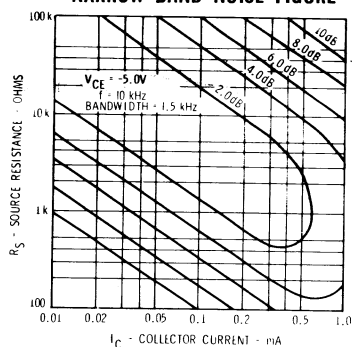
CONTOURS OF CONSTANT
NARROW BAND NOISE FIGURE



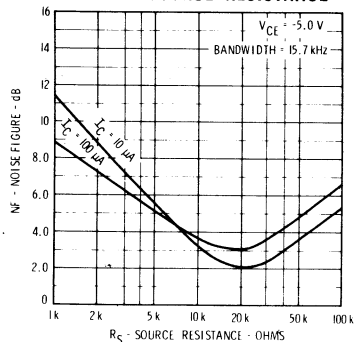
CONTOURS OF CONSTANT
NARROW BAND NOISE FIGURE



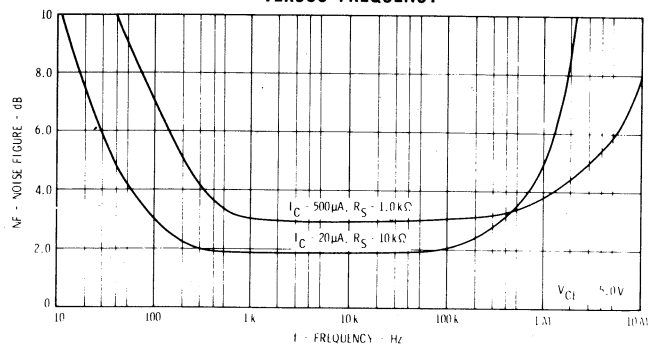
CONTOURS OF CONSTANT
NARROW BAND NOISE FIGURE



WIDE BAND NOISE FIGURE
VERSUS SOURCE RESISTANCE



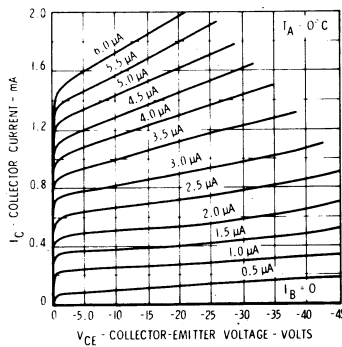
NOISE FIGURE
VERSUS FREQUENCY



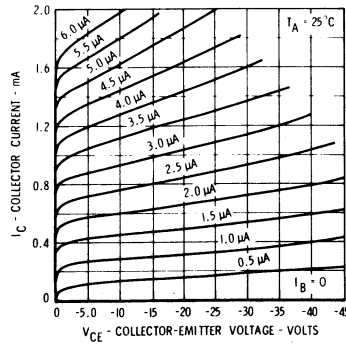
FAIRCHILD TRANSISTOR 2N4359

TYPICAL ELECTRICAL CHARACTERISTICS

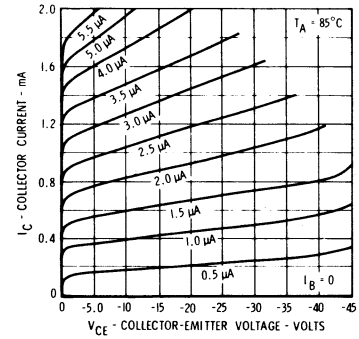
COLLECTOR CHARACTERISTICS*



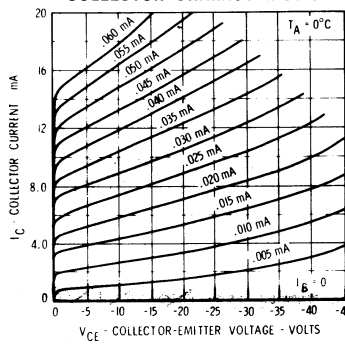
COLLECTOR CHARACTERISTICS*



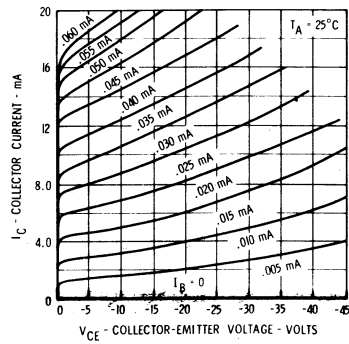
COLLECTOR CHARACTERISTICS*



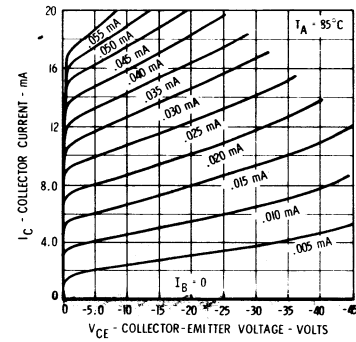
COLLECTOR CHARACTERISTICS*



COLLECTOR CHARACTERISTICS*



COLLECTOR CHARACTERISTICS*



NOTES:

- (1) These ratings are limiting values above which the serviceability of any individual semiconductor device may be impaired.
- (2) These are steady state limits. The factory should be consulted on applications involving pulsed or low-duty cycle operations.
- (3) These ratings give a maximum junction temperature of 200°C and junction to case thermal resistance of $146^\circ\text{C}/\text{Watt}$ (derating factor of $6.85 \text{ mW}/^\circ\text{C}$); junction to ambient thermal resistance of $486^\circ\text{C}/\text{Watt}$ (derating factor of $2.06 \text{ mW}/^\circ\text{C}$).
- (4) This rating refers to a high-current point where collector to emitter voltage is lowest.
- (5) Pulse Conditions: length = $300 \mu\text{s}$; duty cycle = 1%.

* Single family characteristic on Transistor Curve Tracer.